Radiation Report

SN54SLC8T245-SEP Total Ionizing Dose (TID)

TEXAS INSTRUMENTS

ABSTRACT

This report covers the radiation characterization results of the SN54SLC8T245-SEP 8-Bit Dual-Supply Bus Transceiver. The study was done to determine Total Ionizing Dose (TID) effects under high dose rate (HDR) up to 20 krad(Si) as a one time characterization. The results show that all samples passed within the specified limits up to 20 krad(Si). However, Radiation Lot Acceptance Testing (RLAT) will be performed using 34 units at a dose level of 20 krad(Si) for future wafer lots. Furthermore, the SN54SLC8T245-SEP is packaged in a space enhanced plastic for low outgassing characteristics and is Single Event Latch-Up (SEL) immune up to 43 MeV-cm^2/mg making the device suitable for low Earth orbit space applications. The device is ideal for logic level shifting from low voltage FPGAs, controllers, and subsystems.

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1 Device Information

1.1 Product Description

The SN54SLC8T245-SEP device is an 8-bit noninverting bus transceiver that resolves voltage level mismatch between devices operating at the latest voltage nodes (0.7 V, 0.8 V, and 0.9 V) and devices operating at industry standard voltage nodes (1.8 V, 2.5 V, and 3.3 V).The device operates by using two independent powersupply rails (V_{CCA} and V_{CCB}) that operate as low as 0.65 V. Data pins A1 through A8 are designed to track V_{CCA}, which accepts any supply voltage from 0.65 V to 3.6 V. Data pins B1 through B8 are designed to track V_{CCB}, which accepts any supply voltage from 0.65 V to 3.6 V.

The SN54SLC8T245-SEP device is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level of the direction-control inputs (DIR1 and DIR2). The output-enable ($\overline{OE}$) input is used to disable the outputs so the buses are effectively isolated. The control pins (DIR and $\overline{OE}$) are referenced to V_{CCA}.

This device is fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs when the device is powered down. This inhibits current backflow into the device which prevents damage to the device. The V_{CC} isolation feature ensures that if either V_{CC} input supply is below 100 mV, then all level shifter outputs are disabled and placed into a high-impedance state. To ensure the high-impedance state of the level shifter I/Os during power up or power down, $\overline{OE}$ should be tied to V_{CCA} through a pullup resistor; the minimum value of the resistor is determined by the currentsinking capability of the driver

1.2 Device Details

Table 1-1 lists the device information used for TID HDR characterization and qualification.

Table 1-1. Device and Exposure Details

TID HDR Details: up to 20 krad(Si)	
TI Device Number	SN54SLC8T245-SEP
Package	24-pin PW (TSSOP)
Technology	LBC7
Die Lot Number	8269031
A/T Lot Number / Date Code	2242232/23CGH1K
Quantity Tested	34 irradiated devices + 3 control
Lot Accept/Reject	All levels tested and passed up to 20 krad(Si)
HDR Radiation Facility	Texas Instruments – Dallas, TX
HDR Dose Level	10 krad(Si), 30 krad(Si)
HDR Dose Rate	239.5 rad(Si)/s [238 to 241 rad(si)/s]
HDR Radiation Source	Gammacell (Hopewell, GR420) Co-60
Irradiation Temperature	25°C

2 Total Dose Test Setup

2.1 Test Overview

The SN54SLC8T245-SEP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, Condition A was used. The product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production automated test equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The SN54SLC8T245-SEP HDR exposure was performed on biased and unbiased devices in a Co-60 gamma cell at TI facility in Dallas, Texas. The un-attenuated dose rate of this cell is 239.5 rads(Si)/s [238 to 241 rad(Si)/s]. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and full post radiation electrical evaluation using Texas Instruments ATE was conducted. ATE test limits are set per data sheet electrical limits based on qualification and characterization data. Post radiation measurements were taken within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post radiation measurements.

2.3 Test Setup Details

The devices were tested in biased conditions as described in the following section.

2.3.1 Biased

Figure 2-1 shows the bias conditions for each pin during irradiation.

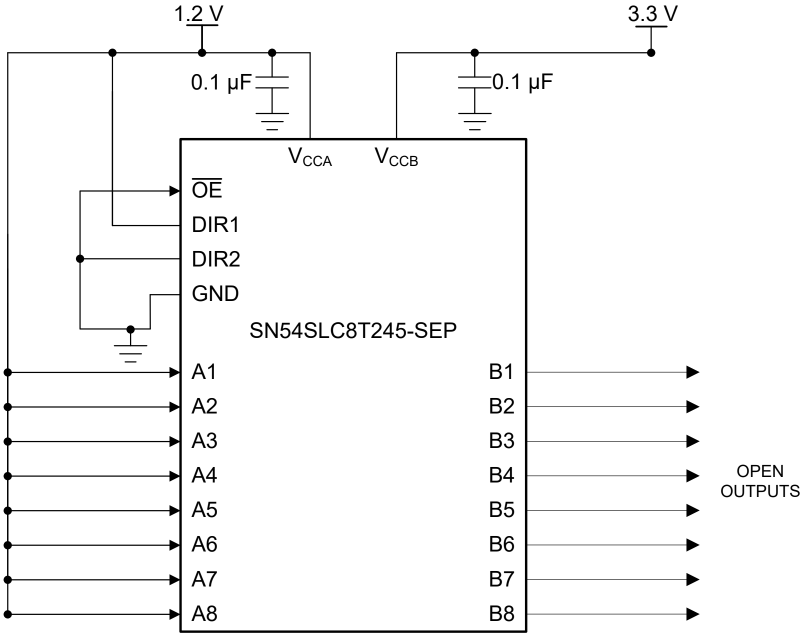


Figure 2-1. SN54SLC8T245-SEP Bias Diagram

2.4 Test Configuration and Condition

HDR devices were stressed at 20 krad(Si) for biased conditions.

Table 2-1. HDR = 20 krad(Si) Biased Device Information

Total Samples: 34	
Exposure Levels	
10 krad(Si)	20 krad(Si)
4, 5, 6	7 – 37

3 TID Characterization Test Results

3.1 TID Characterization Summary Results

The parametric data for the SN54SLC8T245-SEP passes up to 20 krad(Si) HDR TID irradiation. The drifts of the electrical parameters through HDR were within the data sheet limits.

Overall, the SN54SLC8T245-SEP showed a strong degree of hardness to HDR TID irradiation up to 20 krad(Si). The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level. The parameters that did show a greater degree of change between pre- and post-irradiation were still within the electrical performance characteristics specified in the data sheet electrical parameters. For the data sheet electrical parameters and associated tests, see *SN54SLC8T245-SEP Radiation-Tolerant, Eight-Bit, 0.65-V to 3.3-V, Direction-Controlled Level Translator in Space Enhanced Plastic* data sheet.

See Appendix: HDR TID Report Data for HDR report up to 20 krad(Si).

3.2 Specification Compliance Matrix

Table 3-1. SN54SLC8T245-SEP Electrical Parameters Table

PARAMETER		TEST CONDITIONS		V_{CCA}	V_{CCB}	SN54SLC8T245-SEP DATA SHEET				TEST NAME
						MIN	TYP	MAX	UNIT	
V_{OH}	High-level output voltage	$V_I = V_{IH}$	I_{OH} = –50 µA	0.65 V	0.65 V	0.55			V	VOH_50UA
			I_{OH} = –200 µA	0.76 V	0.76 V	0.58				VOH_200UA
			I_{OH} = –500 µA	0.85 V	0.85 V	0.65				VOH_500UA
			I_{OH} = –3 mA	1.1 V	1.1 V	0.85				VOH_3MA
			I_{OH} = –6 mA	1.4 V	1.4 V	1.05				VOH_6MA
			I_{OH} = –8 mA	1.65 V	1.65 V	1.2				VOH_8MA
			I_{OH} = –9 mA	2.3 V	2.3 V	1.75				VOH_9MA
			I_{OH} = –12 mA	3 V	3 V	2.3				VOH_12MA
V_{OL}	Low-level output voltage	$V_I = V_{IL}$	I_{OL} = 50 µA	0.65 V	0.65 V			0.1	V	VOL_50UA
			I_{OL} = 200 µA	0.76 V	0.76 V			0.18		VOL_200UA
			I_{OL} = 500 µA	0.85 V	0.85 V			0.2		VOL_500UA
			I_{OL} = 3 mA	1.1 V	1.1 V			0.25		VOL_3MA
			I_{OL} = 6 mA	1.4 V	1.4 V			0.35		VOL_6MA
			I_{OL} = 8 mA	1.65 V	1.65 V			0.45		VOL_8MA
			I_{OL} = 9 mA	2.3 V	2.3 V			0.55		VOL_9MA
			I_{OL} = 12 mA	3 V	3 V			0.7		VOL_12MA
I_I	Input leakage current	Control Inputs (DIR, $\overline{OE}$): $V_I = V_{CCA}$ or GND		0.65 V – 3.6 V	0.65 V – 3.6 V	–1		1	µA	II
I_{off}	Partial power down current	A Port: V_I or V_O = 0 V – 3.6 V		0 V	0 V – 3.6 V	–35		55	µA	IOFF
		B Port: V_I or V_O = 0 V – 3.6 V		0 V – 3.6 V	0 V	–35		55		
I_{OZ}	High-impedance state output current	A Port: $V_O = V_{CCO}$ or GND, $V_I = V_{CCI}$ or GND, $\overline{OE} = V_{IH}$		3.6 V	3.6 V	–8		8	µA	IOZ
		B Port: $V_O = V_{CCO}$ or GND, $V_I = V_{CCI}$ or GND, $\overline{OE} = V_{IH}$		3.6 V	3.6 V	–8		8		

Table 3-1. SN54SLC8T245-SEP Electrical Parameters Table (continued)

PARAMETER		TEST CONDITIONS	V_{CCA}	V_{CCB}	SN54SLC8T245-SEP DATA SHEET				TEST NAME
					MIN	TYP	MAX	UNIT	
I_{CCA}	V_{CCA} supply current	$V_I = V_{CCI}$ or GND, I_O = 0 mA	0.65 V – 3.6 V	0.65 V – 3.6 V			40	µA	ICCA_0.65v_3.6v
			0 V	3.6 V	–12				ICCA_0V_3.6V
			3.6 V	0 V			35		ICCA_3.6V_0V
I_{CCB}	V_{CCB} supply current	$V_I = V_{CCI}$ or GND, I_O = 0 mA	0.65 V – 3.6 V	0.65 V – 3.6 V			38	µA	ICCB_0.65v_3.6v
			0 V	3.6 V			35		ICCB_0V_3.6V
			3.6 V	0 V	–12				ICCB_3.6V_0V
I_{CCA} + I_{CCB}	Combined supply current	$V_I = V_{CCI}$ or GND, I_O = 0 mA	0.65 V – 3.6 V	0.65 V – 3.6 V			70	µA	ICCA+ICCB

4 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

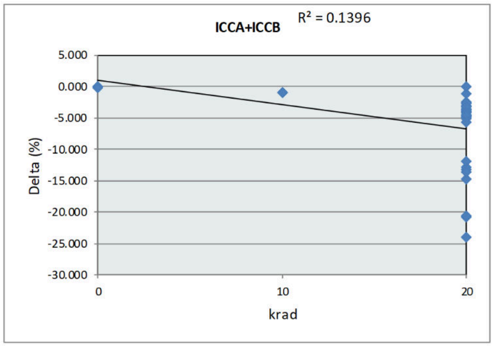
A Appendix: HDR TID Report Data

This appendix provides the SN54SLC8T245-SEP TID HDR report. The report shows the variation for each parameter up to 20 krad(Si).

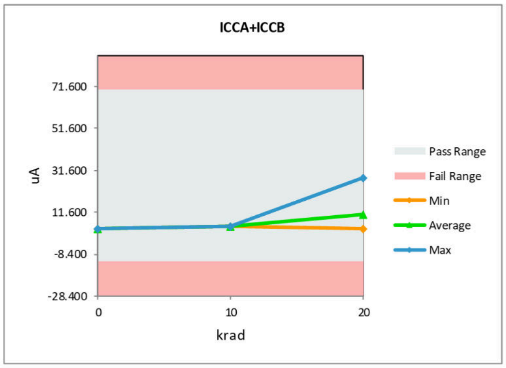
TID Report
SN54SLC8T245-SEP

	ICCA+ICCB	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	70	70
Min Limit	-12	-12

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	3.912	3.916	-0.004	-0.10%	0.00%
0	2	3.866	3.908	-0.042	-1.09%	0.05%
0	3	3.882	3.946	-0.064	-1.65%	0.08%
10	4	3.886	4.772	-0.886	-22.80%	1.08%
10	5	3.883	4.764	-0.881	-22.69%	1.07%
10	6	3.926	4.744	-0.818	-20.84%	1.00%
20	7	3.876	24.533	-20.657	-532.95%	25.19%
20	8	3.906	27.903	-23.997	-614.36%	29.26%
20	9	3.934	24.533	-20.599	-523.61%	25.12%
20	10	3.876	17.001	-13.125	-338.62%	16.01%
20	11	3.906	18.647	-14.741	-377.39%	17.98%
20	12	3.934	16.718	-12.784	-324.96%	15.59%
20	13	3.906	17.538	-13.632	-349.00%	16.62%
20	14	3.934	15.800	-11.866	-301.63%	14.47%
20	15	3.522	6.050	-2.528	-71.78%	3.08%
20	16	3.547	6.720	-3.173	-89.46%	3.87%
20	17	3.453	7.286	-3.833	-111.00%	4.67%
20	18	3.497	8.057	-4.560	-130.40%	5.56%
20	19	3.525	6.148	-2.623	-74.41%	3.20%
20	20	3.516	7.132	-3.616	-102.84%	4.41%
20	21	3.544	8.252	-4.708	-132.84%	5.74%
20	22	3.544	5.946	-2.402	-67.78%	2.93%
20	23	3.578	6.550	-2.972	-83.06%	3.62%
20	24	3.503	7.340	-3.837	-109.53%	4.68%
20	25	3.547	8.324	-4.777	-134.68%	5.83%
20	26	3.512	4.622	-1.110	-31.61%	1.35%
20	27	3.556	7.220	-3.664	-103.04%	4.47%
20	28	3.522	8.211	-4.689	-133.13%	5.72%
20	29	3.528	7.984	-4.456	-126.30%	5.43%
20	30	3.547	6.195	-2.648	-74.65%	3.23%
20	31	3.538	7.088	-3.550	-100.34%	4.33%
20	32	3.553	8.585	-5.032	-141.63%	6.14%
20	33	3.519	6.682	-3.163	-89.88%	3.86%
20	34	3.607	7.720	-4.113	-114.03%	5.02%
20	35	3.541	7.934	-4.393	-124.06%	5.36%
20	36	3.560	9.167	-5.607	-157.50%	6.84%
20	37	3.547	3.582	-0.035	-0.99%	0.04%
	Max	3.934	27.903	-0.004	-0.10%	29.26%
	Average	3.674	9.500	-5.827	-155.04%	7.11%
	Min	3.453	3.582	-23.997	-614.36%	0.00%
	Std Dev	0.182	6.279	6.187	156.64%	7.54%

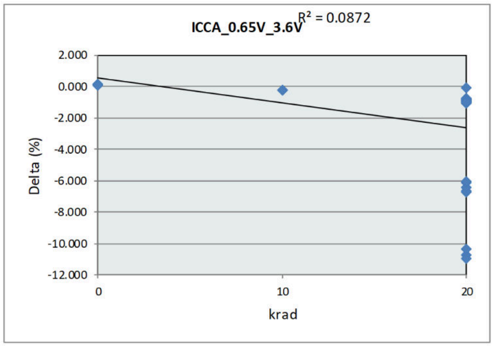


	ICCA+ICCB		
Test Site			
Tester			
Test Number			
Max Limit	70	uA	
Min Limit	-12	uA	
krad	**0**	**10**	**20**
LL	-12.000	-12.000	-12.000
Min	3.908	4.744	3.582
Average	3.923	4.760	10.499
Max	3.946	4.772	27.903
UL	70.000	70.000	70.000

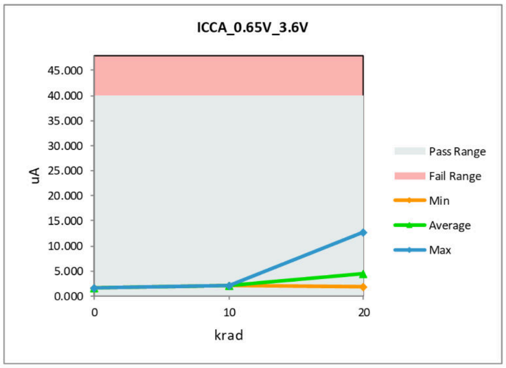


TID Report
SN54SLC8T245-SEP

		ICCA_0.65V_3.6V				
	Test Site					
	Tester					
	Test Number					
	Unit	uA	uA			
	Max Limit	40	40			
	Min Limit	0	0			
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.822	1.662	0.160	8.78%	0.40%
0	2	1.780	1.640	0.140	7.87%	0.35%
0	3	1.783	1.662	0.121	6.79%	0.30%
10	4	1.805	2.037	-0.232	-12.85%	0.58%
10	5	1.808	2.034	-0.226	-12.50%	0.56%
10	6	1.833	2.063	-0.230	-12.55%	0.58%
20	7	1.789	12.510	-10.721	-599.27%	26.80%
20	8	1.819	12.719	-10.900	-599.23%	27.25%
20	9	1.850	12.164	-10.314	-557.51%	25.79%
20	10	1.789	8.513	-6.724	-375.85%	16.81%
20	11	1.819	8.416	-6.597	-362.67%	16.49%
20	12	1.850	8.281	-6.431	-347.62%	16.08%
20	13	1.819	7.923	-6.104	-335.57%	15.26%
20	14	1.850	7.845	-5.995	-324.05%	14.99%
20	15	1.789	2.521	-0.732	-40.92%	1.83%
20	16	1.752	2.587	-0.835	-47.66%	2.09%
20	17	1.748	2.594	-0.846	-48.40%	2.12%
20	18	1.780	2.694	-0.914	-51.35%	2.29%
20	19	1.764	2.550	-0.786	-44.56%	1.97%
20	20	1.767	2.625	-0.858	-48.56%	2.15%
20	21	1.780	2.735	-0.955	-53.65%	2.39%
20	22	1.786	2.578	-0.792	-44.34%	1.98%
20	23	1.789	2.584	-0.795	-44.44%	1.99%
20	24	1.755	2.666	-0.911	-51.91%	2.28%
20	25	1.755	2.694	-0.939	-53.50%	2.35%
20	26	1.767	2.496	-0.729	-41.26%	1.82%
20	27	1.792	2.669	-0.877	-48.94%	2.19%
20	28	1.767	2.672	-0.905	-51.22%	2.26%
20	29	1.780	2.789	-1.009	-56.69%	2.52%
20	30	1.792	2.559	-0.767	-42.80%	1.92%
20	31	1.796	2.647	-0.851	-47.38%	2.13%
20	32	1.767	2.829	-1.062	-60.10%	2.66%
20	33	1.789	2.622	-0.833	-46.56%	2.08%
20	34	1.833	2.741	-0.908	-49.54%	2.27%
20	35	1.780	2.713	-0.933	-52.42%	2.33%
20	36	1.818	2.804	-0.986	-54.24%	2.47%
20	37	1.767	1.799	-0.032	-1.81%	0.08%
	Max	1.850	12.719	0.160	8.78%	27.25%
	Average	1.793	4.044	-2.252	-124.28%	5.69%
	Min	1.748	1.640	-10.900	-599.27%	0.08%
	Std Dev	0.028	3.233	3.219	176.62%	8.01%



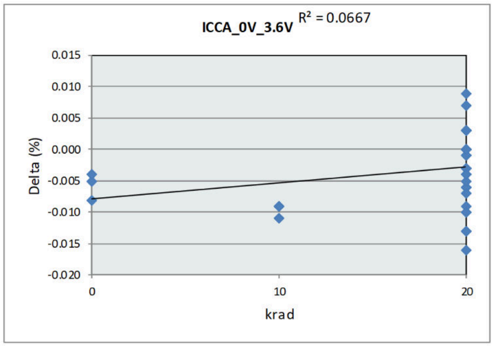
	ICCA_0.65V_3.6V		
Test Site			
Tester			
Test Number			
Max Limit	40	uA	
Min Limit	0	uA	
krad	0	10	20
LL	0.000	0.000	0.000
Min	1.640	2.034	1.799
Average	1.655	2.045	4.469
Max	1.662	2.063	12.719
UL	40.000	40.000	40.000



TID Report
SN54SLC8T245-SEP

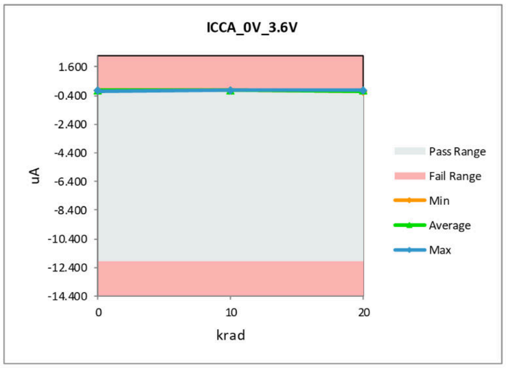
	ICCA_0V_3.6V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	0	0
Min Limit	-12	-12

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	-0.011	-0.003	-0.008	72.73%	0.07%
0	2	-0.008	-0.003	-0.005	62.50%	0.04%
0	3	-0.007	-0.003	-0.004	57.14%	0.03%
10	4	-0.012	-0.003	-0.009	75.00%	0.08%
10	5	-0.013	-0.002	-0.011	84.62%	0.09%
10	6	-0.009	0.000	-0.009	100.00%	0.08%
20	7	-0.008	-0.007	-0.001	12.50%	0.01%
20	8	-0.012	-0.003	-0.009	75.00%	0.08%
20	9	-0.009	-0.003	-0.006	66.67%	0.05%
20	10	-0.008	-0.007	-0.001	12.50%	0.01%
20	11	-0.012	0.001	-0.013	108.33%	0.11%
20	12	-0.009	-0.003	-0.006	66.67%	0.05%
20	13	-0.012	-0.021	0.009	-75.00%	0.08%
20	14	-0.009	-0.004	-0.005	55.56%	0.04%
20	15	-0.081	-0.078	-0.003	3.70%	0.03%
20	16	-0.078	-0.078	0.000	0.00%	0.00%
20	17	-0.074	-0.071	-0.003	4.05%	0.03%
20	18	-0.078	-0.071	-0.007	8.97%	0.06%
20	19	-0.071	-0.068	-0.003	4.23%	0.02%
20	20	-0.078	-0.081	0.003	-3.85%	0.03%
20	21	-0.078	-0.074	-0.004	5.13%	0.03%
20	22	-0.074	-0.081	0.007	-9.46%	0.06%
20	23	-0.078	-0.081	0.003	-3.85%	0.03%
20	24	-0.078	-0.081	0.003	-3.85%	0.03%
20	25	-0.078	-0.078	0.000	0.00%	0.00%
20	26	-0.071	-0.074	0.003	-4.23%	0.03%
20	27	-0.078	-0.078	0.000	0.00%	0.00%
20	28	-0.078	-0.068	-0.010	12.82%	0.08%
20	29	-0.081	-0.071	-0.010	12.35%	0.08%
20	30	-0.078	-0.074	-0.004	5.13%	0.03%
20	31	-0.081	-0.084	0.003	-3.70%	0.03%
20	32	-0.078	-0.078	0.000	0.00%	0.00%
20	33	-0.081	-0.081	0.000	0.00%	0.00%
20	34	-0.084	-0.068	-0.016	19.05%	0.13%
20	35	-0.078	-0.081	0.003	-3.85%	0.03%
20	36	-0.081	-0.068	-0.013	16.05%	0.11%
20	37	-0.074	-0.074	0.000	0.00%	0.00%
	Max	-0.007	0.001	0.009	108.33%	0.13%
	Average	-0.052	-0.049	-0.003	22.51%	0.04%
	Min	-0.084	-0.084	-0.016	-75.00%	0.00%
	Std Dev	0.033	0.035	0.006	38.39%	0.04%



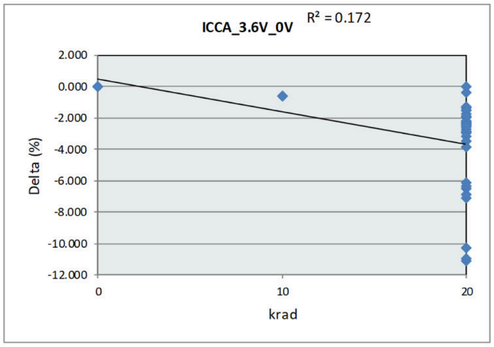
	ICCA_0V_3.6V	
Test Site		
Tester		
Test Number		
Max Limit	0	uA
Min Limit	-12	uA

krad	0	10	20
LL	-12.000	-12.000	-12.000
Min	-0.003	-0.003	-0.084
Average	-0.003	-0.002	-0.058
Max	-0.003	0.000	0.001
UL	0.000	0.000	0.000

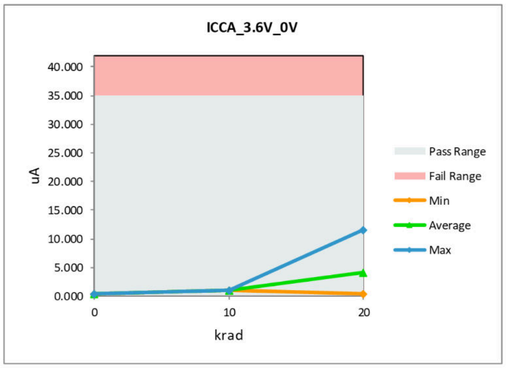


TID Report
SN54SLC8T245-SEP

		ICCA_3.6V_0V				
	Test Site					
	Tester					
	Test Number					
	Unit	uA	uA			
	Max Limit	35	35			
	Min Limit	0	0			
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.370	0.371	-0.001	-0.27%	0.00%
0	2	0.373	0.379	-0.006	-1.61%	0.02%
0	3	0.366	0.370	-0.004	-1.09%	0.01%
10	4	0.376	0.948	-0.572	-152.13%	1.63%
10	5	0.373	0.966	-0.593	-158.98%	1.69%
10	6	0.380	0.937	-0.557	-146.58%	1.59%
20	7	0.367	11.463	-11.096	-3023.43%	31.70%
20	8	0.372	11.269	-10.897	-2929.30%	31.13%
20	9	0.384	10.631	-10.247	-2668.49%	29.28%
20	10	0.367	7.435	-7.068	-1925.89%	20.19%
20	11	0.372	7.191	-6.819	-1833.06%	19.48%
20	12	0.384	6.883	-6.499	-1692.45%	18.57%
20	13	0.372	6.719	-6.347	-1706.18%	18.13%
20	14	0.384	6.465	-6.081	-1583.59%	17.37%
20	15	0.403	1.774	-1.371	-340.20%	3.92%
20	16	0.410	2.122	-1.712	-417.56%	4.89%
20	17	0.394	2.748	-2.354	-597.46%	6.73%
20	18	0.394	3.238	-2.844	-721.83%	8.13%
20	19	0.403	1.931	-1.528	-379.16%	4.37%
20	20	0.397	2.644	-2.247	-565.99%	6.42%
20	21	0.406	3.131	-2.725	-671.18%	7.79%
20	22	0.397	1.692	-1.295	-326.20%	3.70%
20	23	0.397	2.320	-1.923	-484.38%	5.49%
20	24	0.397	2.732	-2.335	-588.16%	6.67%
20	25	0.394	3.332	-2.938	-745.69%	8.39%
20	26	0.406	0.765	-0.359	-88.42%	1.03%
20	27	0.403	2.587	-2.184	-541.94%	6.24%
20	28	0.397	3.232	-2.835	-714.11%	8.10%
20	29	0.394	3.577	-3.183	-807.87%	9.09%
20	30	0.397	1.893	-1.496	-376.83%	4.27%
20	31	0.403	2.814	-2.411	-598.26%	6.89%
20	32	0.403	3.854	-3.451	-856.33%	9.86%
20	33	0.413	2.289	-1.876	-454.24%	5.36%
20	34	0.403	2.974	-2.571	-637.97%	7.35%
20	35	0.403	2.842	-2.439	-605.21%	6.97%
20	36	0.410	4.256	-3.846	-938.05%	10.99%
20	37	0.400	0.406	-0.006	-1.50%	0.02%
	Max	0.413	11.463	-0.001	-0.27%	31.70%
	Average	0.391	3.545	-3.154	-818.42%	9.01%
	Min	0.366	0.370	-11.096	-3023.43%	0.00%
	Std Dev	0.014	2.987	2.992	805.61%	8.55%



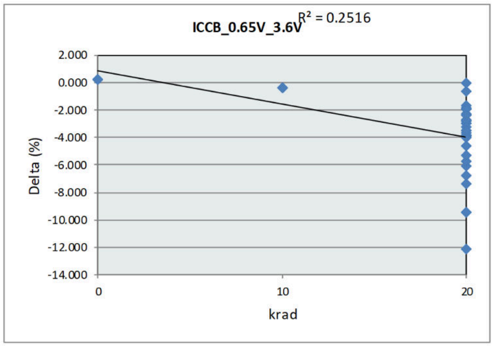
	ICCA_3.6V_0V		
Test Site			
Tester			
Test Number			
Max Limit	35	uA	
Min Limit	0	uA	
krad	0	10	20
LL	0.000	0.000	0.000
Min	0.370	0.937	0.406
Average	0.373	0.950	4.104
Max	0.379	0.966	11.463
UL	35.000	35.000	35.000



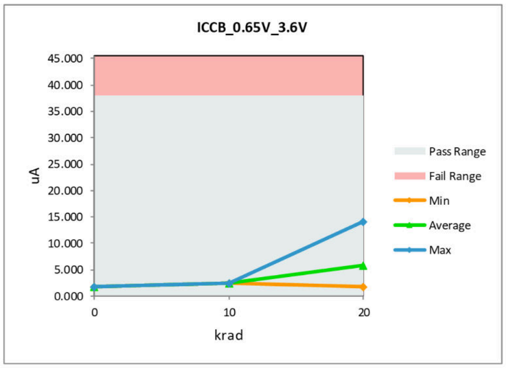
TID Report
SN54SLC8T245-SEP

	ICCB_0.65V_3.6V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	38	38
Min Limit	0	0

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	2.109	1.859	0.250	11.85%	0.66%
0	2	2.115	1.862	0.253	11.96%	0.67%
0	3	2.118	1.871	0.247	11.66%	0.65%
10	4	2.091	2.449	-0.358	-17.12%	0.94%
10	5	2.088	2.474	-0.386	-18.49%	1.02%
10	6	2.109	2.452	-0.343	-16.26%	0.90%
20	7	2.107	11.529	-9.422	-447.18%	24.79%
20	8	2.098	14.154	-12.056	-574.64%	31.73%
20	9	2.098	11.509	-9.411	-448.57%	24.77%
20	10	2.107	8.114	-6.007	-285.10%	15.81%
20	11	2.098	9.440	-7.342	-349.95%	19.32%
20	12	2.098	7.787	-5.689	-271.16%	14.97%
20	13	2.098	8.867	-6.769	-322.64%	17.81%
20	14	2.098	7.329	-5.231	-249.33%	13.77%
20	15	1.821	3.651	-1.830	-100.49%	4.82%
20	16	1.836	4.214	-2.378	-129.52%	6.26%
20	17	1.789	4.749	-2.960	-165.46%	7.79%
20	18	1.818	5.454	-3.636	-200.00%	9.57%
20	19	1.836	3.699	-1.863	-101.47%	4.90%
20	20	1.818	4.573	-2.755	-151.54%	7.25%
20	21	1.840	5.605	-3.765	-204.62%	9.91%
20	22	1.833	3.469	-1.636	-89.25%	4.31%
20	23	1.849	4.067	-2.218	-119.96%	5.84%
20	24	1.824	4.755	-2.931	-160.69%	7.71%
20	25	1.833	5.699	-3.866	-210.91%	10.17%
20	26	1.827	2.437	-0.610	-33.39%	1.61%
20	27	1.843	4.642	-2.799	-151.87%	7.37%
20	28	1.827	5.611	-3.784	-207.12%	9.96%
20	29	1.836	5.278	-3.442	-187.47%	9.06%
20	30	1.843	3.717	-1.874	-101.68%	4.93%
20	31	1.840	4.494	-2.654	-144.24%	6.98%
20	32	1.836	5.841	-4.005	-218.14%	10.54%
20	33	1.821	4.148	-2.327	-127.79%	6.12%
20	34	1.862	5.079	-3.217	-172.77%	8.47%
20	35	1.830	5.300	-3.470	-189.62%	9.13%
20	36	1.836	6.444	-4.608	-250.98%	12.13%
20	37	1.824	1.858	-0.034	-1.86%	0.09%
	Max	2.118	14.154	0.253	11.96%	31.73%
	Average	1.934	5.310	-3.376	-172.59%	8.99%
	Min	1.789	1.858	-12.056	-574.64%	0.09%
	Std Dev	0.134	2.901	2.860	135.63%	7.39%



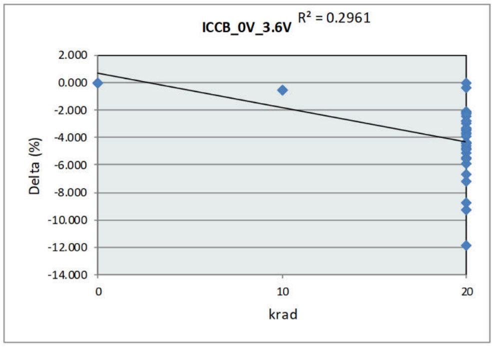
	ICCB_0.65V_3.6V		
Test Site			
Tester			
Test Number			
Max Limit	38	uA	
Min Limit	0	uA	
krad	0	10	20
LL	0.000	0.000	0.000
Min	1.859	2.449	1.858
Average	1.864	2.458	5.920
Max	1.871	2.474	14.154
UL	38.000	38.000	38.000



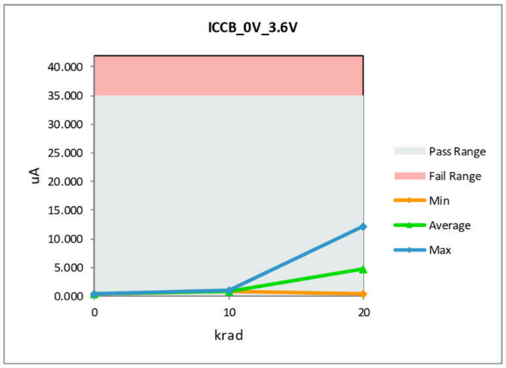
TID Report
SN54SLC8T245-SEP

	ICCB_0V_3.6V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	35	35
Min Limit	0	0

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.368	0.369	-0.001	-0.27%	0.00%
0	2	0.365	0.370	-0.005	-1.37%	0.01%
0	3	0.364	0.369	-0.005	-1.37%	0.01%
10	4	0.376	0.914	-0.538	-143.09%	1.54%
10	5	0.364	0.925	-0.561	-154.12%	1.60%
10	6	0.373	0.904	-0.531	-142.36%	1.52%
20	7	0.372	9.628	-9.256	-2488.17%	26.45%
20	8	0.374	12.244	-11.870	-3173.80%	33.91%
20	9	0.375	9.124	-8.749	-2333.07%	25.00%
20	10	0.372	6.279	-5.907	-1587.90%	16.88%
20	11	0.374	7.585	-7.211	-1928.07%	20.60%
20	12	0.375	5.831	-5.456	-1454.93%	15.59%
20	13	0.374	7.039	-6.665	-1782.09%	19.04%
20	14	0.375	5.450	-5.075	-1353.33%	14.50%
20	15	0.402	2.569	-2.167	-539.05%	6.19%
20	16	0.399	3.327	-2.928	-733.83%	8.37%
20	17	0.399	4.085	-3.686	-923.81%	10.53%
20	18	0.399	4.825	-4.426	-1109.27%	12.65%
20	19	0.405	2.830	-2.425	-598.77%	6.93%
20	20	0.405	3.758	-3.353	-827.90%	9.58%
20	21	0.412	5.211	-4.799	-1164.81%	13.71%
20	22	0.408	2.456	-2.048	-501.96%	5.85%
20	23	0.405	3.170	-2.765	-682.72%	7.90%
20	24	0.396	4.016	-3.620	-914.14%	10.34%
20	25	0.386	5.101	-4.715	-1221.50%	13.47%
20	26	0.405	0.767	-0.362	-89.38%	1.03%
20	27	0.396	3.862	-3.466	-875.25%	9.90%
20	28	0.405	5.001	-4.596	-1134.81%	13.13%
20	29	0.396	4.784	-4.388	-1108.08%	12.54%
20	30	0.386	2.651	-2.265	-586.79%	6.47%
20	31	0.396	3.654	-3.258	-822.73%	9.31%
20	32	0.396	5.215	-4.819	-1216.92%	13.77%
20	33	0.399	3.148	-2.749	-688.97%	7.85%
20	34	0.405	4.287	-3.882	-958.52%	11.09%
20	35	0.405	4.699	-4.294	-1060.25%	12.27%
20	36	0.393	5.932	-5.539	-1409.41%	15.83%
20	37	0.389	0.405	-0.016	-4.11%	0.05%
	Max	0.412	12.244	-0.001	-0.27%	33.91%
	Average	0.389	4.129	-3.740	-965.32%	10.69%
	Min	0.364	0.369	-11.870	-3173.80%	0.00%
	Std Dev	0.015	2.738	2.740	732.42%	7.83%

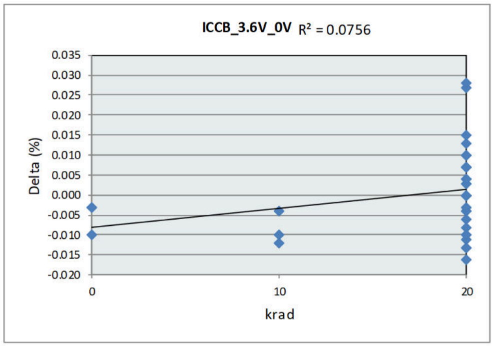


	ICCB_0V_3.6V		
Test Site			
Tester			
Test Number			
Max Limit	35	uA	
Min Limit	0	uA	
krad	0	10	20
LL	0.000	0.000	0.000
Min	0.369	0.904	0.405
Average	0.369	0.914	4.804
Max	0.370	0.925	12.244
UL	35.000	35.000	35.000

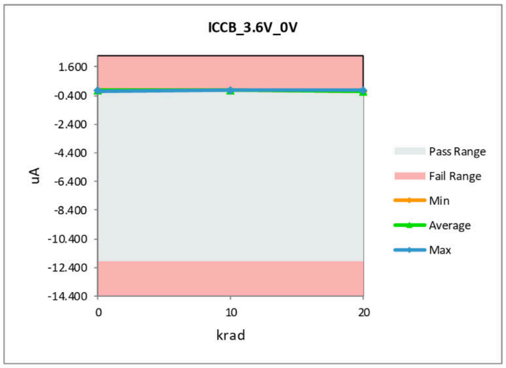


TID Report
SN54SLC8T245-SEP

		ICCB_3.6V_0V				
	Test Site					
	Tester					
	Test Number					
	Unit	uA	uA			
	Max Limit	0	0			
	Min Limit	-12	-12			
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	-0.008	-0.005	-0.003	37.50%	0.03%
0	2	-0.013	-0.003	-0.010	76.92%	0.08%
0	3	-0.009	-0.006	-0.003	33.33%	0.03%
10	4	-0.011	-0.001	-0.010	90.91%	0.08%
10	5	-0.014	-0.002	-0.012	85.71%	0.10%
10	6	-0.008	-0.004	-0.004	50.00%	0.03%
20	7	-0.010	-0.025	0.015	-150.00%	0.13%
20	8	-0.013	-0.005	-0.008	61.54%	0.07%
20	9	-0.014	-0.003	-0.011	78.57%	0.09%
20	10	-0.010	-0.017	0.007	-70.00%	0.06%
20	11	-0.013	0.000	-0.013	100.00%	0.11%
20	12	-0.014	-0.004	-0.010	71.43%	0.08%
20	13	-0.013	-0.040	0.027	-207.69%	0.23%
20	14	-0.014	-0.042	0.028	-200.00%	0.23%
20	15	-0.082	-0.085	0.003	-3.66%	0.03%
20	16	-0.082	-0.082	0.000	0.00%	0.00%
20	17	-0.092	-0.076	-0.016	17.39%	0.13%
20	18	-0.079	-0.079	0.000	0.00%	0.00%
20	19	-0.089	-0.085	-0.004	4.49%	0.03%
20	20	-0.085	-0.089	0.004	-4.71%	0.03%
20	21	-0.085	-0.095	0.010	-11.76%	0.08%
20	22	-0.082	-0.082	0.000	0.00%	0.00%
20	23	-0.085	-0.085	0.000	0.00%	0.00%
20	24	-0.089	-0.092	0.003	-3.37%	0.03%
20	25	-0.089	-0.085	-0.004	4.49%	0.03%
20	26	-0.089	-0.079	-0.010	11.24%	0.08%
20	27	-0.082	-0.089	0.007	-8.54%	0.06%
20	28	-0.095	-0.082	-0.013	13.68%	0.11%
20	29	-0.082	-0.089	0.007	-8.54%	0.06%
20	30	-0.085	-0.082	-0.003	3.53%	0.03%
20	31	-0.082	-0.082	0.000	0.00%	0.00%
20	32	-0.082	-0.076	-0.006	7.32%	0.05%
20	33	-0.082	-0.089	0.007	-8.54%	0.06%
20	34	-0.085	-0.098	0.013	-15.29%	0.11%
20	35	-0.085	-0.089	0.004	-4.71%	0.03%
20	36	-0.079	-0.089	0.010	-12.66%	0.08%
20	37	-0.085	-0.092	0.007	-8.24%	0.06%
	Max	-0.008	0.000	0.028	100.00%	0.23%
	Average	-0.057	-0.058	0.000	0.82%	0.07%
	Min	-0.095	-0.098	-0.016	-207.69%	0.00%
	Std Dev	0.036	0.038	0.010	67.44%	0.05%



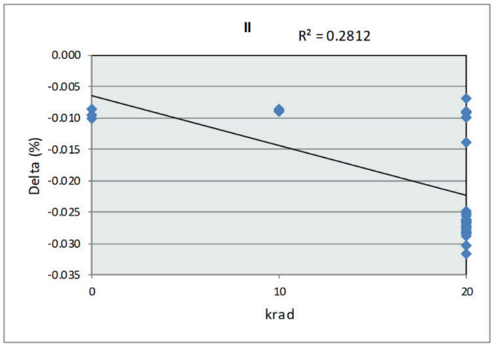
	ICCB_3.6V_0V		
Test Site			
Tester			
Test Number			
Max Limit	0	uA	
Min Limit	-12	uA	
krad	0	10	20
LL	-12.000	-12.000	-12.000
Min	-0.006	-0.004	-0.098
Average	-0.005	-0.002	-0.068
Max	-0.003	-0.001	0.000
UL	0.000	0.000	0.000



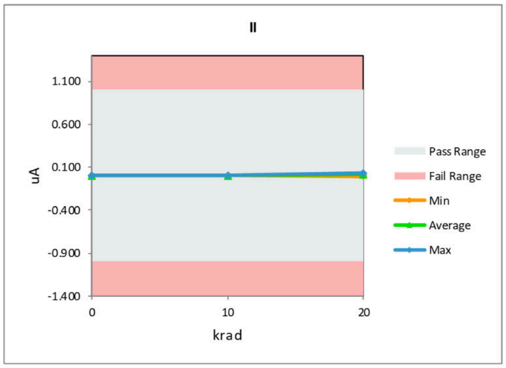
TID Report
SN54SLC8T245-SEP

	II	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	1	1
Min Limit	-1	-1

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	-0.002	0.008	-0.010	506.78%	0.50%
0	2	-0.003	0.006	-0.009	330.77%	0.43%
0	3	-0.002	0.007	-0.009	383.78%	0.47%
10	4	-0.003	0.006	-0.009	304.55%	0.45%
10	5	-0.003	0.006	-0.009	327.85%	0.43%
10	6	-0.003	0.006	-0.009	325.00%	0.43%
20	7	-0.003	0.006	-0.009	293.55%	0.46%
20	8	-0.003	0.011	-0.014	488.24%	0.69%
20	9	-0.002	0.008	-0.010	528.57%	0.49%
20	10	-0.003	0.006	-0.009	293.55%	0.46%
20	11	-0.003	0.006	-0.009	311.76%	0.44%
20	12	-0.002	0.007	-0.009	475.00%	0.44%
20	13	-0.003	0.007	-0.010	347.06%	0.49%
20	14	-0.002	0.005	-0.007	367.86%	0.34%
20	15	-0.001	0.026	-0.027	3103.30%	1.36%
20	16	-0.003	0.028	-0.030	1185.68%	1.51%
20	17	0.001	0.026	-0.025	-2484.65%	1.24%
20	18	0.001	0.027	-0.026	-5017.42%	1.32%
20	19	-0.001	0.027	-0.028	2739.92%	1.42%
20	20	0.000	0.026	-0.026	-8156.73%	1.30%
20	21	0.001	0.027	-0.027	-4611.06%	1.34%
20	22	-0.001	0.026	-0.027	2620.00%	1.36%
20	23	-0.001	0.027	-0.028	4469.81%	1.38%
20	24	-0.001	0.027	-0.028	2367.73%	1.41%
20	25	-0.002	0.026	-0.028	1215.73%	1.42%
20	26	0.001	0.027	-0.026	-5015.81%	1.32%
20	27	-0.003	0.029	-0.032	1169.26%	1.58%
20	28	0.000	0.026	-0.026	58322.06%	1.32%
20	29	0.000	0.025	-0.025	-9416.64%	1.26%
20	30	0.001	0.027	-0.027	-3366.33%	1.33%
20	31	0.000	0.025	-0.025	#######	1.26%
20	32	-0.002	0.026	-0.028	1253.66%	1.40%
20	33	0.001	0.027	-0.026	-2269.83%	1.31%
20	34	0.000	0.028	-0.027	#######	1.37%
20	35	0.000	0.026	-0.025	-7961.21%	1.27%
20	36	-0.001	0.026	-0.026	4266.37%	1.32%
20	37	-0.002	0.027	-0.029	1677.81%	1.44%
	Max	0.001	0.029	-0.007	58322.06%	1.58%
	Average	-0.001	0.019	-0.020	-8863.57%	1.02%
	Min	-0.003	0.005	-0.032	#######	0.34%
	Std Dev	0.001	0.010	0.009	60079.44%	0.45%



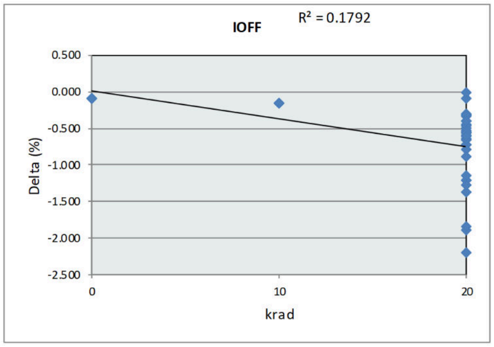
	II		
Test Site			
Tester			
Test Number			
Max Limit	1	uA	
Min Limit	-1	uA	
krad	0	10	20
LL	-1.000	-1.000	-1.000
Min	0.006	0.006	0.005
Average	0.007	0.006	0.022
Max	0.008	0.006	0.029
UL	1.000	1.000	1.000



TID Report
SN54SLC8T245-SEP

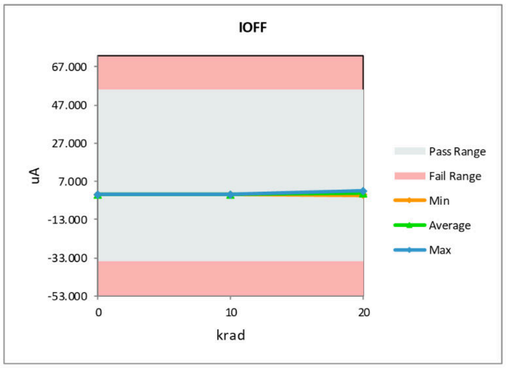
	IOFF	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	55	55
Min Limit	-35	-35

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.042	0.131	-0.089	-211.67%	0.10%
0	2	0.042	0.131	-0.089	-209.60%	0.10%
0	3	0.042	0.131	-0.089	-210.21%	0.10%
10	4	0.043	0.196	-0.153	-360.84%	0.17%
10	5	0.042	0.195	-0.153	-367.77%	0.17%
10	6	0.044	0.200	-0.156	-359.33%	0.17%
20	7	0.042	1.919	-1.877	-4419.73%	2.09%
20	8	0.042	2.239	-2.197	-5191.58%	2.44%
20	9	0.044	1.884	-1.840	-4213.47%	2.04%
20	10	0.042	1.251	-1.209	-2846.42%	1.34%
20	11	0.042	1.413	-1.371	-3239.44%	1.52%
20	12	0.044	1.255	-1.211	-2773.36%	1.35%
20	13	0.042	1.311	-1.269	-2998.38%	1.41%
20	14	0.044	1.187	-1.143	-2617.67%	1.27%
20	15	0.099	0.431	-0.332	-336.20%	0.37%
20	16	0.100	0.534	-0.435	-436.43%	0.48%
20	17	0.096	0.632	-0.536	-557.07%	0.60%
20	18	0.097	0.742	-0.645	-668.06%	0.72%
20	19	0.097	0.409	-0.312	-321.12%	0.35%
20	20	0.097	0.583	-0.486	-499.72%	0.54%
20	21	0.100	0.817	-0.717	-720.45%	0.80%
20	22	0.098	0.393	-0.295	-300.11%	0.33%
20	23	0.097	0.497	-0.400	-412.03%	0.44%
20	24	0.099	0.655	-0.557	-564.62%	0.62%
20	25	0.098	0.811	-0.714	-730.60%	0.79%
20	26	0.097	0.184	-0.087	-89.49%	0.10%
20	27	0.096	0.559	-0.464	-484.72%	0.52%
20	28	0.097	0.737	-0.640	-656.63%	0.71%
20	29	0.096	0.682	-0.587	-613.90%	0.65%
20	30	0.097	0.414	-0.317	-325.90%	0.35%
20	31	0.097	0.613	-0.517	-534.32%	0.57%
20	32	0.097	0.872	-0.775	-800.58%	0.86%
20	33	0.097	0.488	-0.391	-400.81%	0.43%
20	34	0.099	0.659	-0.560	-563.74%	0.62%
20	35	0.098	0.703	-0.605	-615.32%	0.67%
20	36	0.099	0.982	-0.883	-895.07%	0.98%
20	37	0.098	0.105	-0.007	-7.00%	0.01%
	Max	0.100	2.239	-0.007	-7.00%	2.44%
	Average	0.077	0.728	-0.651	-1123.06%	0.72%
	Min	0.042	0.105	-2.197	-5191.58%	0.01%
	Std Dev	0.027	0.526	0.535	1364.40%	0.59%



	IOFF	
Test Site		
Tester		
Test Number		
Max Limit	55	uA
Min Limit	-35	uA

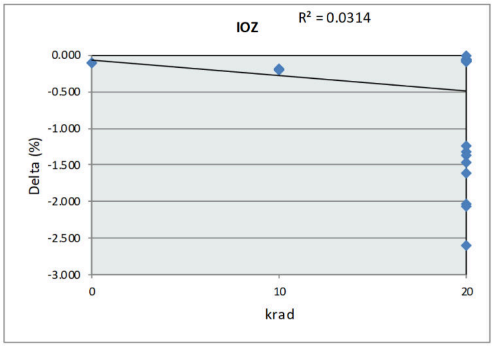
krad	0	10	20
LL	-35.000	-35.000	-35.000
Min	0.131	0.195	0.105
Average	0.131	0.197	0.838
Max	0.131	0.200	2.239
UL	55.000	55.000	55.000



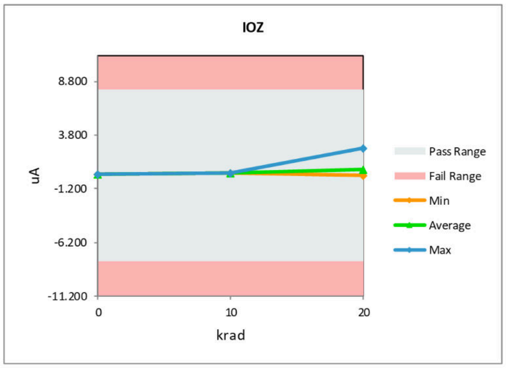
TID Report
SN54SLC8T245-SEP

	IOZ	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	8	8
Min Limit	-8	-8

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.027	0.133	-0.106	-386.77%	0.66%
0	2	0.027	0.134	-0.107	-398.80%	0.67%
0	3	0.027	0.135	-0.108	-397.89%	0.67%
10	4	0.027	0.210	-0.183	-667.12%	1.14%
10	5	0.027	0.217	-0.190	-702.77%	1.19%
10	6	0.028	0.218	-0.190	-687.06%	1.19%
20	7	0.027	2.055	-2.028	-7435.52%	12.67%
20	8	0.027	2.616	-2.589	-9511.02%	16.18%
20	9	0.028	2.088	-2.061	-7492.73%	12.88%
20	10	0.027	1.347	-1.320	-4839.34%	8.25%
20	11	0.027	1.633	-1.606	-5899.54%	10.04%
20	12	0.028	1.387	-1.360	-4943.64%	8.50%
20	13	0.027	1.480	-1.453	-5337.43%	9.08%
20	14	0.028	1.254	-1.227	-4460.00%	7.67%
20	15	0.067	0.125	-0.058	-87.91%	0.37%
20	16	0.067	0.140	-0.073	-108.80%	0.46%
20	17	0.066	0.133	-0.067	-101.02%	0.42%
20	18	0.067	0.135	-0.068	-101.73%	0.42%
20	19	0.066	0.129	-0.063	-95.80%	0.40%
20	20	0.067	0.136	-0.069	-103.58%	0.43%
20	21	0.068	0.146	-0.077	-113.01%	0.48%
20	22	0.067	0.127	-0.059	-88.65%	0.37%
20	23	0.067	0.133	-0.067	-100.25%	0.42%
20	24	0.066	0.142	-0.076	-115.06%	0.47%
20	25	0.066	0.140	-0.074	-112.09%	0.46%
20	26	0.067	0.128	-0.062	-92.74%	0.39%
20	27	0.065	0.145	-0.080	-123.45%	0.50%
20	28	0.067	0.134	-0.067	-100.80%	0.42%
20	29	0.066	0.142	-0.076	-114.94%	0.47%
20	30	0.067	0.127	-0.060	-89.25%	0.37%
20	31	0.067	0.134	-0.067	-99.85%	0.42%
20	32	0.065	0.145	-0.080	-122.70%	0.50%
20	33	0.068	0.131	-0.064	-93.61%	0.40%
20	34	0.069	0.141	-0.072	-104.85%	0.45%
20	35	0.068	0.137	-0.069	-100.71%	0.43%
20	36	0.067	0.138	-0.070	-104.87%	0.44%
20	37	0.066	0.072	-0.006	-9.33%	0.04%
	Max	0.069	2.616	-0.006	-9.33%	16.18%
	Average	0.052	0.486	-0.434	-1498.50%	2.71%
	Min	0.027	0.072	-2.589	-9511.02%	0.04%
	Std Dev	0.019	0.697	0.710	2645.55%	4.43%



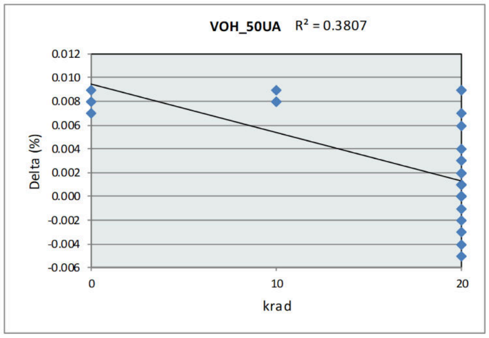
	IOZ		
Test Site			
Tester			
Test Number			
Max Limit	8	uA	
Min Limit	-8	uA	
krad	0	10	20
LL	-8.000	-8.000	-8.000
Min	0.133	0.210	0.072
Average	0.134	0.215	0.546
Max	0.135	0.218	2.616
UL	8.000	8.000	8.000



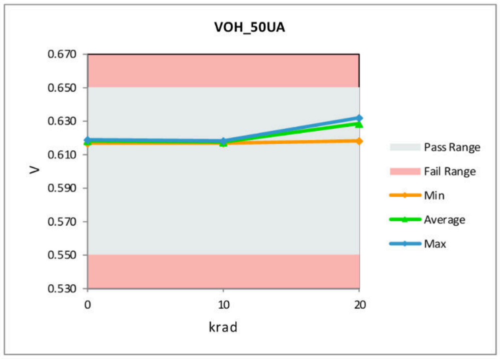
TID Report
SN54SLC8T245-SEP

	VOH_50UA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.65	0.65
Min Limit	0.55	0.55

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.626	0.619	0.007	1.12%	7.00%
0	2	0.627	0.619	0.008	1.28%	8.00%
0	3	0.626	0.617	0.009	1.44%	9.00%
10	4	0.626	0.618	0.008	1.28%	8.00%
10	5	0.626	0.617	0.009	1.44%	9.00%
10	6	0.626	0.618	0.008	1.28%	8.00%
20	7	0.627	0.618	0.009	1.44%	9.00%
20	8	0.626	0.619	0.007	1.12%	7.00%
20	9	0.627	0.618	0.009	1.44%	9.00%
20	10	0.627	0.621	0.006	0.96%	6.00%
20	11	0.626	0.622	0.004	0.64%	4.00%
20	12	0.627	0.624	0.003	0.48%	3.00%
20	13	0.626	0.631	-0.005	-0.80%	5.00%
20	14	0.627	0.631	-0.004	-0.64%	4.00%
20	15	0.632	0.632	0.000	0.00%	0.00%
20	16	0.633	0.632	0.001	0.16%	1.00%
20	17	0.632	0.632	0.000	0.00%	0.00%
20	18	0.631	0.630	0.001	0.16%	1.00%
20	19	0.630	0.630	0.000	0.00%	0.00%
20	20	0.631	0.631	0.000	0.00%	0.00%
20	21	0.630	0.629	0.001	0.16%	1.00%
20	22	0.630	0.628	0.002	0.32%	2.00%
20	23	0.629	0.632	-0.003	-0.48%	3.00%
20	24	0.632	0.631	0.001	0.16%	1.00%
20	25	0.631	0.631	0.000	0.00%	0.00%
20	26	0.631	0.629	0.002	0.32%	2.00%
20	27	0.629	0.631	-0.002	-0.32%	2.00%
20	28	0.631	0.629	0.002	0.32%	2.00%
20	29	0.629	0.629	0.000	0.00%	0.00%
20	30	0.629	0.629	0.000	0.00%	0.00%
20	31	0.630	0.629	0.001	0.16%	1.00%
20	32	0.629	0.629	0.000	0.00%	0.00%
20	33	0.631	0.631	0.000	0.00%	0.00%
20	34	0.629	0.629	0.000	0.00%	0.00%
20	35	0.632	0.632	0.000	0.00%	0.00%
20	36	0.629	0.630	-0.001	-0.16%	1.00%
20	37	0.632	0.629	0.003	0.47%	3.00%
	Max	0.633	0.632	0.009	1.44%	9.00%
	Average	0.629	0.627	0.002	0.37%	3.14%
	Min	0.626	0.617	-0.005	-0.80%	0.00%
	Std Dev	0.002	0.005	0.004	0.63%	3.30%



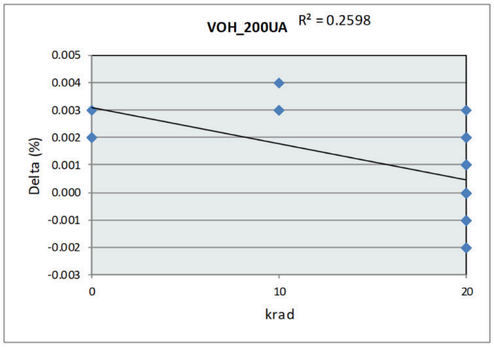
	VOH_50UA		
Test Site			
Tester			
Test Number			
Max Limit	0.65	V	
Min Limit	0.55	V	
krad	0	10	20
LL	0.550	0.550	0.550
Min	0.617	0.617	0.618
Average	0.618	0.618	0.628
Max	0.619	0.618	0.632
UL	0.650	0.650	0.650



TID Report
SN54SLC8T245-SEP

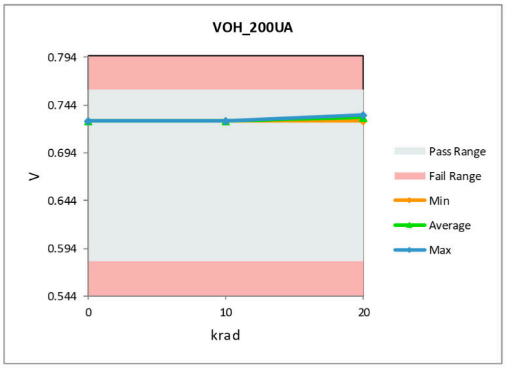
	VOH_200UA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.76	0.76
Min Limit	0.58	0.58

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.730	0.728	0.002	0.27%	1.11%
0	2	0.730	0.728	0.002	0.27%	1.11%
0	3	0.730	0.727	0.003	0.41%	1.67%
10	4	0.730	0.727	0.003	0.41%	1.67%
10	5	0.730	0.727	0.003	0.41%	1.67%
10	6	0.731	0.727	0.004	0.55%	2.22%
20	7	0.730	0.727	0.003	0.41%	1.67%
20	8	0.730	0.728	0.002	0.27%	1.11%
20	9	0.730	0.728	0.002	0.27%	1.11%
20	10	0.730	0.728	0.002	0.27%	1.11%
20	11	0.730	0.729	0.001	0.14%	0.56%
20	12	0.730	0.729	0.001	0.14%	0.56%
20	13	0.730	0.732	-0.002	-0.27%	1.11%
20	14	0.730	0.732	-0.002	-0.27%	1.11%
20	15	0.734	0.734	0.000	0.00%	0.00%
20	16	0.734	0.734	0.000	0.00%	0.00%
20	17	0.734	0.734	0.000	0.00%	0.00%
20	18	0.732	0.731	0.001	0.14%	0.56%
20	19	0.732	0.731	0.001	0.14%	0.56%
20	20	0.732	0.732	0.000	0.00%	0.00%
20	21	0.732	0.731	0.001	0.14%	0.56%
20	22	0.732	0.730	0.002	0.27%	1.11%
20	23	0.731	0.733	-0.002	-0.27%	1.11%
20	24	0.733	0.732	0.001	0.14%	0.56%
20	25	0.732	0.732	0.000	0.00%	0.00%
20	26	0.732	0.731	0.001	0.14%	0.56%
20	27	0.731	0.732	-0.001	-0.14%	0.56%
20	28	0.733	0.731	0.002	0.27%	1.11%
20	29	0.731	0.731	0.000	0.00%	0.00%
20	30	0.730	0.731	-0.001	-0.14%	0.56%
20	31	0.731	0.731	0.000	0.00%	0.00%
20	32	0.731	0.730	0.001	0.14%	0.56%
20	33	0.732	0.733	-0.001	-0.14%	0.56%
20	34	0.730	0.731	-0.001	-0.14%	0.56%
20	35	0.733	0.733	0.000	0.00%	0.00%
20	36	0.731	0.732	-0.001	-0.14%	0.56%
20	37	0.733	0.731	0.002	0.27%	1.11%
	Max	0.734	0.734	0.004	0.55%	2.22%
	Average	0.731	0.730	0.001	0.11%	0.77%
	Min	0.730	0.727	-0.002	-0.27%	0.00%
	Std Dev	0.001	0.002	0.002	0.21%	0.58%



	VOH_200UA	
Test Site		
Tester		
Test Number		
Max Limit	0.76	V
Min Limit	0.58	V

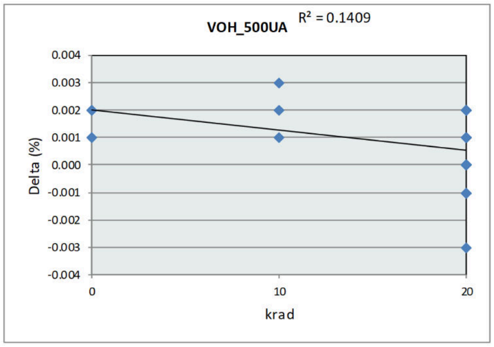
krad	0	10	20
LL	0.580	0.580	0.580
Min	0.727	0.727	0.727
Average	0.728	0.727	0.731
Max	0.728	0.727	0.734
UL	0.760	0.760	0.760



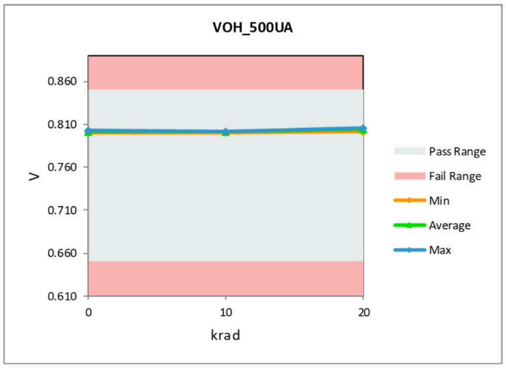
TID Report
SN54SLC8T245-SEP

	VOH_500UA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.85	0.85
Min Limit	0.65	0.65

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.804	0.802	0.002	0.25%	1.00%
0	2	0.804	0.803	0.001	0.12%	0.50%
0	3	0.803	0.801	0.002	0.25%	1.00%
10	4	0.804	0.802	0.002	0.25%	1.00%
10	5	0.803	0.802	0.001	0.12%	0.50%
10	6	0.804	0.801	0.003	0.37%	1.50%
20	7	0.804	0.802	0.002	0.25%	1.00%
20	8	0.804	0.802	0.002	0.25%	1.00%
20	9	0.804	0.802	0.002	0.25%	1.00%
20	10	0.804	0.803	0.001	0.12%	0.50%
20	11	0.804	0.803	0.001	0.12%	0.50%
20	12	0.804	0.803	0.001	0.12%	0.50%
20	13	0.804	0.804	0.000	0.00%	0.00%
20	14	0.804	0.803	0.001	0.12%	0.50%
20	15	0.806	0.806	0.000	0.00%	0.00%
20	16	0.806	0.806	0.000	0.00%	0.00%
20	17	0.806	0.806	0.000	0.00%	0.00%
20	18	0.804	0.804	0.000	0.00%	0.00%
20	19	0.804	0.804	0.000	0.00%	0.00%
20	20	0.805	0.804	0.001	0.12%	0.50%
20	21	0.804	0.803	0.001	0.12%	0.50%
20	22	0.804	0.803	0.001	0.12%	0.50%
20	23	0.803	0.806	-0.003	-0.37%	1.50%
20	24	0.806	0.805	0.001	0.12%	0.50%
20	25	0.805	0.804	0.001	0.12%	0.50%
20	26	0.805	0.803	0.002	0.25%	1.00%
20	27	0.804	0.804	0.000	0.00%	0.00%
20	28	0.805	0.803	0.002	0.25%	1.00%
20	29	0.803	0.803	0.000	0.00%	0.00%
20	30	0.803	0.803	0.000	0.00%	0.00%
20	31	0.803	0.804	-0.001	-0.12%	0.50%
20	32	0.804	0.803	0.001	0.12%	0.50%
20	33	0.805	0.805	0.000	0.00%	0.00%
20	34	0.803	0.803	0.000	0.00%	0.00%
20	35	0.805	0.806	-0.001	-0.12%	0.50%
20	36	0.803	0.804	-0.001	-0.12%	0.50%
20	37	0.806	0.804	0.002	0.25%	1.00%
	Max	0.806	0.806	0.003	0.37%	1.50%
	Average	0.804	0.803	0.001	0.09%	0.53%
	Min	0.803	0.801	-0.003	-0.37%	0.00%
	Std Dev	0.001	0.001	0.001	0.15%	0.44%



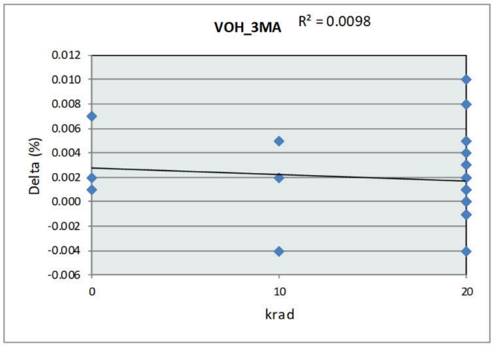
	VOH_500UA		
Test Site			
Tester			
Test Number			
Max Limit	0.85	V	
Min Limit	0.65	V	
krad	0	10	20
LL	0.650	0.650	0.650
Min	0.801	0.801	0.802
Average	0.802	0.802	0.804
Max	0.803	0.802	0.806
UL	0.850	0.850	0.850



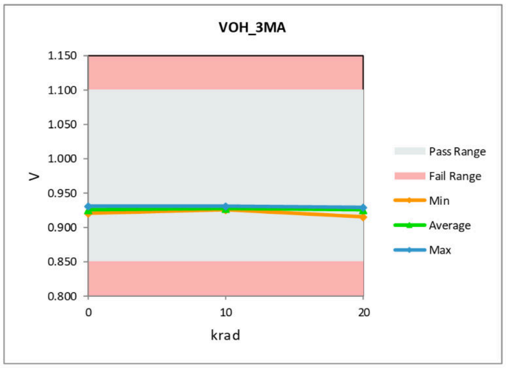
TID Report
SN54SLC8T245-SEP

	VOH_3MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.1	1.1
Min Limit	0.85	0.85

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.931	0.929	0.002	0.21%	0.80%
0	2	0.931	0.930	0.001	0.11%	0.40%
0	3	0.927	0.920	0.007	0.76%	2.80%
10	4	0.926	0.930	-0.004	-0.43%	1.60%
10	5	0.930	0.925	0.005	0.54%	2.00%
10	6	0.931	0.929	0.002	0.21%	0.80%
20	7	0.930	0.929	0.001	0.11%	0.40%
20	8	0.931	0.928	0.003	0.32%	1.20%
20	9	0.931	0.928	0.003	0.32%	1.20%
20	10	0.930	0.929	0.001	0.11%	0.40%
20	11	0.931	0.929	0.002	0.21%	0.80%
20	12	0.931	0.923	0.008	0.86%	3.20%
20	13	0.931	0.927	0.004	0.43%	1.60%
20	14	0.931	0.923	0.008	0.86%	3.20%
20	15	0.929	0.928	0.001	0.11%	0.40%
20	16	0.929	0.929	0.000	0.00%	0.00%
20	17	0.927	0.927	0.000	0.00%	0.00%
20	18	0.925	0.925	0.000	0.00%	0.00%
20	19	0.924	0.924	0.000	0.00%	0.00%
20	20	0.926	0.925	0.001	0.11%	0.40%
20	21	0.925	0.924	0.001	0.11%	0.40%
20	22	0.924	0.922	0.002	0.22%	0.80%
20	23	0.923	0.927	-0.004	-0.43%	1.60%
20	24	0.928	0.926	0.002	0.22%	0.80%
20	25	0.926	0.925	0.001	0.11%	0.40%
20	26	0.926	0.924	0.002	0.22%	0.80%
20	27	0.925	0.915	0.010	1.08%	4.00%
20	28	0.926	0.921	0.005	0.54%	2.00%
20	29	0.924	0.923	0.001	0.11%	0.40%
20	30	0.923	0.924	-0.001	-0.11%	0.40%
20	31	0.924	0.924	0.000	0.00%	0.00%
20	32	0.924	0.922	0.002	0.22%	0.80%
20	33	0.926	0.926	0.000	0.00%	0.00%
20	34	0.922	0.923	-0.001	-0.11%	0.40%
20	35	0.926	0.927	-0.001	-0.11%	0.40%
20	36	0.924	0.925	-0.001	-0.11%	0.40%
20	37	0.928	0.923	0.005	0.54%	2.00%
	Max	0.931	0.930	0.010	1.08%	4.00%
	Average	0.927	0.925	0.002	0.20%	0.99%
	Min	0.922	0.915	-0.004	-0.43%	0.00%
	Std Dev	0.003	0.003	0.003	0.33%	1.01%



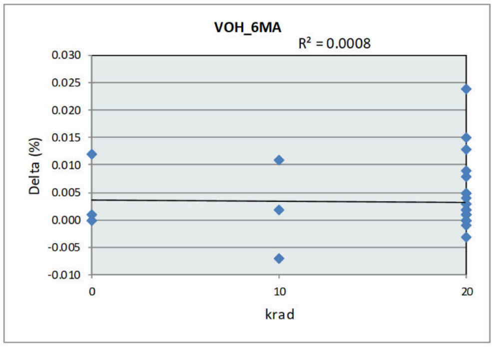
	VOH_3MA		
Test Site			
Tester			
Test Number			
Max Limit	1.1	V	
Min Limit	0.85	V	
krad	0	10	20
LL	0.850	0.850	0.850
Min	0.920	0.925	0.915
Average	0.926	0.928	0.925
Max	0.930	0.930	0.929
UL	1.100	1.100	1.100



TID Report
SN54SLC8T245-SEP

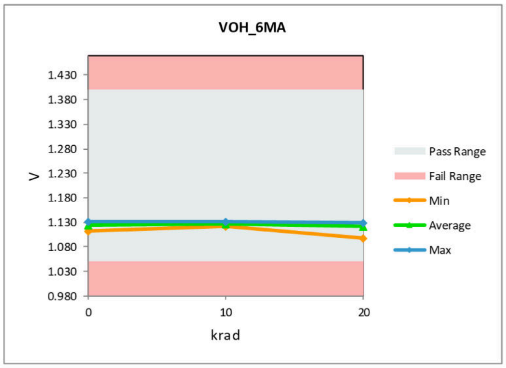
	VOH_6MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.4	1.4
Min Limit	1.05	1.05

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.132	1.131	0.001	0.09%	0.29%
0	2	1.132	1.132	0.000	0.00%	0.00%
0	3	1.124	1.112	0.012	1.07%	3.43%
10	4	1.125	1.132	-0.007	-0.62%	2.00%
10	5	1.132	1.121	0.011	0.97%	3.14%
10	6	1.132	1.130	0.002	0.18%	0.57%
20	7	1.131	1.130	0.001	0.09%	0.29%
20	8	1.132	1.127	0.005	0.44%	1.43%
20	9	1.132	1.127	0.005	0.44%	1.43%
20	10	1.131	1.128	0.003	0.27%	0.86%
20	11	1.132	1.128	0.004	0.35%	1.14%
20	12	1.132	1.117	0.015	1.33%	4.29%
20	13	1.132	1.124	0.008	0.71%	2.29%
20	14	1.132	1.119	0.013	1.15%	3.71%
20	15	1.125	1.125	0.000	0.00%	0.00%
20	16	1.126	1.126	0.000	0.00%	0.00%
20	17	1.124	1.124	0.000	0.00%	0.00%
20	18	1.122	1.121	0.001	0.09%	0.29%
20	19	1.122	1.122	0.000	0.00%	0.00%
20	20	1.123	1.123	0.000	0.00%	0.00%
20	21	1.122	1.121	0.001	0.09%	0.29%
20	22	1.122	1.120	0.002	0.18%	0.57%
20	23	1.120	1.123	-0.003	-0.27%	0.86%
20	24	1.124	1.122	0.002	0.18%	0.57%
20	25	1.122	1.122	0.000	0.00%	0.00%
20	26	1.123	1.121	0.002	0.18%	0.57%
20	27	1.122	1.098	0.024	2.14%	6.86%
20	28	1.123	1.114	0.009	0.80%	2.57%
20	29	1.122	1.121	0.001	0.09%	0.29%
20	30	1.121	1.121	0.000	0.00%	0.00%
20	31	1.122	1.121	0.001	0.09%	0.29%
20	32	1.122	1.120	0.002	0.18%	0.57%
20	33	1.122	1.123	-0.001	-0.09%	0.29%
20	34	1.120	1.120	0.000	0.00%	0.00%
20	35	1.123	1.123	0.000	0.00%	0.00%
20	36	1.121	1.121	0.000	0.00%	0.00%
20	37	1.124	1.121	0.003	0.27%	0.86%
	Max	1.132	1.132	0.024	2.14%	6.86%
	Average	1.126	1.122	0.003	0.28%	1.07%
	Min	1.120	1.098	-0.007	-0.62%	0.00%
	Std Dev	0.005	0.006	0.006	0.51%	1.53%



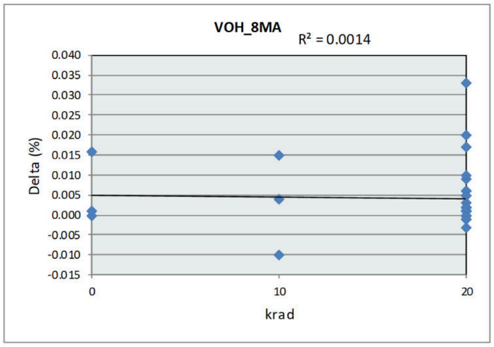
	VOH_6MA		
Test Site			
Tester			
Test Number			
Max Limit	1.4	V	
Min Limit	1.05	V	

krad	0	10	20
LL	1.050	1.050	1.050
Min	1.112	1.121	1.098
Average	1.125	1.128	1.122
Max	1.132	1.132	1.130
UL	1.400	1.400	1.400

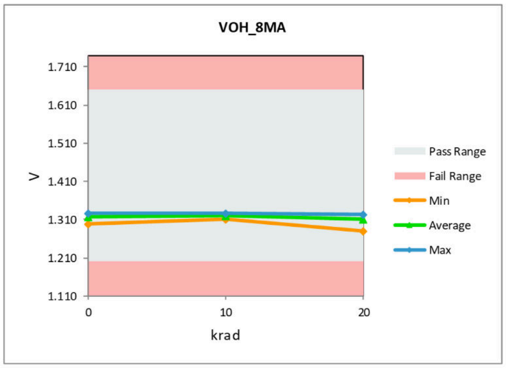


TID Report
SN54SLC8T245-SEP

		VOH_8MA				
	Test Site					
	Tester					
	Test Number					
	Unit	V	V			
	Max Limit	1.65	1.65			
	Min Limit	1.2	1.2			
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.326	1.326	0.000	0.00%	0.00%
0	2	1.327	1.326	0.001	0.08%	0.22%
0	3	1.316	1.300	0.016	1.22%	3.56%
10	4	1.317	1.327	-0.010	-0.76%	2.22%
10	5	1.326	1.311	0.015	1.13%	3.33%
10	6	1.327	1.323	0.004	0.30%	0.89%
20	7	1.326	1.324	0.002	0.15%	0.44%
20	8	1.326	1.320	0.006	0.45%	1.33%
20	9	1.326	1.320	0.006	0.45%	1.33%
20	10	1.326	1.321	0.005	0.38%	1.11%
20	11	1.326	1.321	0.005	0.38%	1.11%
20	12	1.326	1.306	0.020	1.51%	4.44%
20	13	1.326	1.317	0.009	0.68%	2.00%
20	14	1.326	1.309	0.017	1.28%	3.78%
20	15	1.315	1.315	0.000	0.00%	0.00%
20	16	1.316	1.315	0.001	0.08%	0.22%
20	17	1.313	1.313	0.000	0.00%	0.00%
20	18	1.312	1.311	0.001	0.08%	0.22%
20	19	1.312	1.312	0.000	0.00%	0.00%
20	20	1.313	1.312	0.001	0.08%	0.22%
20	21	1.313	1.312	0.001	0.08%	0.22%
20	22	1.312	1.310	0.002	0.15%	0.44%
20	23	1.311	1.314	-0.003	-0.23%	0.67%
20	24	1.314	1.312	0.002	0.15%	0.44%
20	25	1.313	1.312	0.001	0.08%	0.22%
20	26	1.313	1.312	0.001	0.08%	0.22%
20	27	1.313	1.280	0.033	2.51%	7.33%
20	28	1.313	1.303	0.010	0.76%	2.22%
20	29	1.312	1.311	0.001	0.08%	0.22%
20	30	1.312	1.312	0.000	0.00%	0.00%
20	31	1.313	1.312	0.001	0.08%	0.22%
20	32	1.313	1.310	0.003	0.23%	0.67%
20	33	1.312	1.313	-0.001	-0.08%	0.22%
20	34	1.311	1.310	0.001	0.08%	0.22%
20	35	1.313	1.313	0.000	0.00%	0.00%
20	36	1.311	1.312	-0.001	-0.08%	0.22%
20	37	1.314	1.312	0.002	0.15%	0.44%
	Max	1.327	1.327	0.033	2.51%	7.33%
	Average	1.317	1.313	0.004	0.31%	1.09%
	Min	1.311	1.280	-0.010	-0.76%	0.00%
	Std Dev	0.006	0.008	0.008	0.58%	1.58%



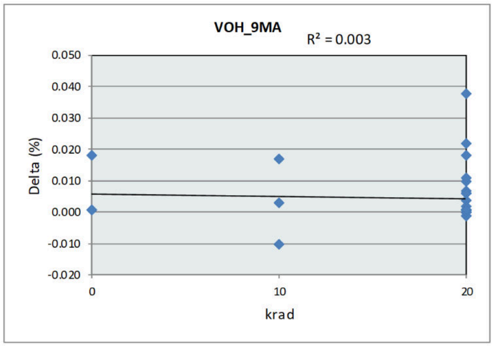
	VOH_8MA		
Test Site			
Tester			
Test Number			
Max Limit	1.65	V	
Min Limit	1.2	V	
krad	0	10	20
LL	1.200	1.200	1.200
Min	1.300	1.311	1.280
Average	1.317	1.320	1.312
Max	1.326	1.327	1.324
UL	1.650	1.650	1.650



TID Report
SN54SLC8T245-SEP

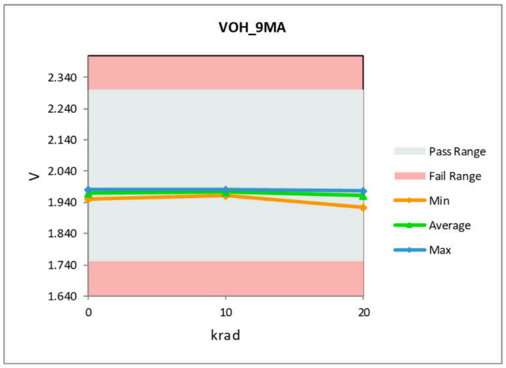
	VOH_9MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2.3	2.3
Min Limit	1.75	1.75

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.979	1.978	0.001	0.05%	0.18%
0	2	1.980	1.979	0.001	0.05%	0.18%
0	3	1.968	1.950	0.018	0.91%	3.27%
10	4	1.969	1.979	-0.010	-0.51%	1.82%
10	5	1.979	1.962	0.017	0.86%	3.09%
10	6	1.979	1.976	0.003	0.15%	0.55%
20	7	1.978	1.977	0.001	0.05%	0.18%
20	8	1.979	1.973	0.006	0.30%	1.09%
20	9	1.979	1.972	0.007	0.35%	1.27%
20	10	1.978	1.974	0.004	0.20%	0.73%
20	11	1.979	1.973	0.006	0.30%	1.09%
20	12	1.979	1.957	0.022	1.11%	4.00%
20	13	1.979	1.969	0.010	0.51%	1.82%
20	14	1.979	1.961	0.018	0.91%	3.27%
20	15	1.965	1.965	0.000	0.00%	0.00%
20	16	1.966	1.965	0.001	0.05%	0.18%
20	17	1.963	1.963	0.000	0.00%	0.00%
20	18	1.963	1.962	0.001	0.05%	0.18%
20	19	1.963	1.962	0.001	0.05%	0.18%
20	20	1.963	1.963	0.000	0.00%	0.00%
20	21	1.963	1.963	0.000	0.00%	0.00%
20	22	1.963	1.962	0.001	0.05%	0.18%
20	23	1.962	1.963	-0.001	-0.05%	0.18%
20	24	1.964	1.963	0.001	0.05%	0.18%
20	25	1.963	1.963	0.000	0.00%	0.00%
20	26	1.963	1.962	0.001	0.05%	0.18%
20	27	1.963	1.925	0.038	1.94%	6.91%
20	28	1.963	1.952	0.011	0.56%	2.00%
20	29	1.963	1.962	0.001	0.05%	0.18%
20	30	1.963	1.963	0.000	0.00%	0.00%
20	31	1.963	1.962	0.001	0.05%	0.18%
20	32	1.964	1.962	0.002	0.10%	0.36%
20	33	1.962	1.963	-0.001	-0.05%	0.18%
20	34	1.962	1.961	0.001	0.05%	0.18%
20	35	1.964	1.963	0.001	0.05%	0.18%
20	36	1.962	1.962	0.000	0.00%	0.00%
20	37	1.963	1.962	0.001	0.05%	0.18%
	Max	1.980	1.979	0.038	1.94%	6.91%
	Average	1.969	1.964	0.004	0.22%	0.92%
	Min	1.962	1.925	-0.010	-0.51%	0.00%
	Std Dev	0.007	0.010	0.009	0.43%	1.48%



	VOH_9MA	
Test Site		
Tester		
Test Number		
Max Limit	2.3	V
Min Limit	1.75	V

krad	0	10	20
LL	1.750	1.750	1.750
Min	1.950	1.962	1.925
Average	1.969	1.972	1.963
Max	1.979	1.979	1.977
UL	2.300	2.300	2.300



TID Report
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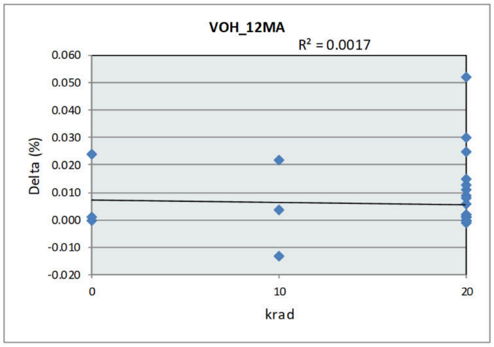
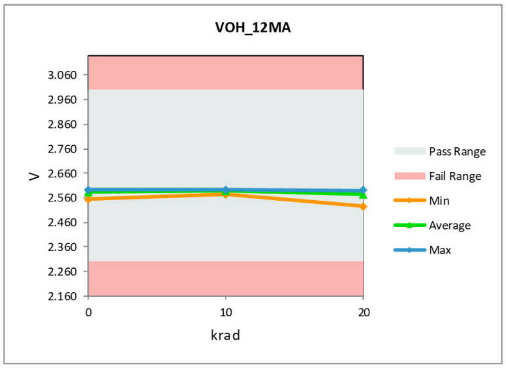
	VOH_12MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3	3
Min Limit	2.3	2.3

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	2.596	2.596	0.000	0.00%	0.00%
0	2	2.597	2.596	0.001	0.04%	0.14%
0	3	2.581	2.557	0.024	0.93%	3.43%
10	4	2.583	2.596	-0.013	-0.50%	1.86%
10	5	2.596	2.574	0.022	0.85%	3.14%
10	6	2.597	2.593	0.004	0.15%	0.57%
20	7	2.595	2.593	0.002	0.08%	0.29%
20	8	2.596	2.587	0.009	0.35%	1.29%
20	9	2.597	2.586	0.011	0.42%	1.57%
20	10	2.595	2.589	0.006	0.23%	0.86%
20	11	2.596	2.588	0.008	0.31%	1.14%
20	12	2.597	2.567	0.030	1.16%	4.29%
20	13	2.596	2.583	0.013	0.50%	1.86%
20	14	2.597	2.572	0.025	0.96%	3.57%
20	15	2.577	2.577	0.000	0.00%	0.00%
20	16	2.578	2.577	0.001	0.04%	0.14%
20	17	2.576	2.576	0.000	0.00%	0.00%
20	18	2.575	2.574	0.001	0.04%	0.14%
20	19	2.575	2.575	0.000	0.00%	0.00%
20	20	2.575	2.575	0.000	0.00%	0.00%
20	21	2.576	2.576	0.000	0.00%	0.00%
20	22	2.576	2.574	0.002	0.08%	0.29%
20	23	2.574	2.575	-0.001	-0.04%	0.14%
20	24	2.576	2.575	0.001	0.04%	0.14%
20	25	2.575	2.575	0.000	0.00%	0.00%
20	26	2.575	2.575	0.000	0.00%	0.00%
20	27	2.576	2.524	0.052	2.02%	7.43%
20	28	2.575	2.560	0.015	0.58%	2.14%
20	29	2.575	2.575	0.000	0.00%	0.00%
20	30	2.576	2.575	0.001	0.04%	0.14%
20	31	2.576	2.575	0.001	0.04%	0.14%
20	32	2.576	2.575	0.001	0.04%	0.14%
20	33	2.575	2.575	0.000	0.00%	0.00%
20	34	2.575	2.574	0.001	0.04%	0.14%
20	35	2.575	2.575	0.000	0.00%	0.00%
20	36	2.575	2.575	0.000	0.00%	0.00%
20	37	2.575	2.575	0.000	0.00%	0.00%
	Max	2.597	2.596	0.052	2.02%	7.43%
	Average	2.583	2.577	0.006	0.23%	0.95%
	Min	2.574	2.524	-0.013	-0.50%	0.00%
	Std Dev	0.010	0.013	0.012	0.45%	1.61%



	VOH_12MA	
Test Site		
Tester		
Test Number		
Max Limit	3	V
Min Limit	2.3	V

krad	0	10	20
LL	2.300	2.300	2.300
Min	2.557	2.574	2.524
Average	2.583	2.588	2.575
Max	2.596	2.596	2.593
UL	3.000	3.000	3.000



TID Report
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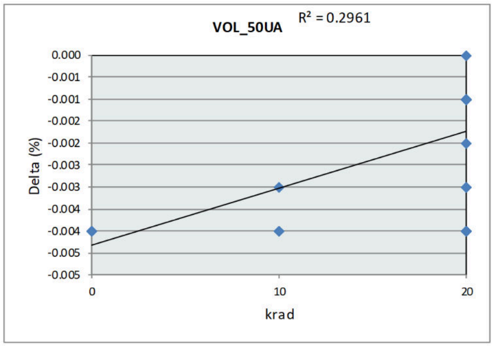
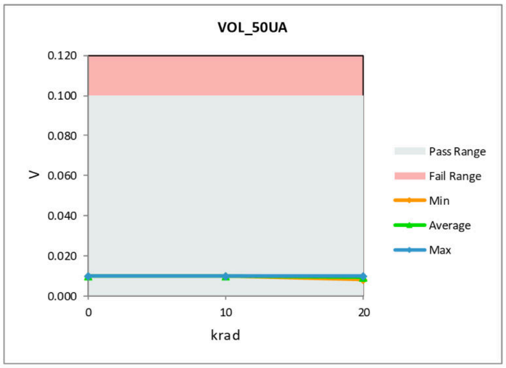
		VOL_50UA				
	Test Site					
	Tester					
	Test Number					
	Unit	V	V			
	Max Limit	0.1	0.1			
	Min Limit	0	0			
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.006	0.010	-0.004	-66.67%	4.00%
0	2	0.006	0.010	-0.004	-66.67%	4.00%
0	3	0.006	0.010	-0.004	-66.67%	4.00%
10	4	0.006	0.010	-0.004	-66.67%	4.00%
10	5	0.006	0.010	-0.004	-66.67%	4.00%
10	6	0.007	0.010	-0.003	-42.86%	3.00%
20	7	0.007	0.010	-0.003	-42.86%	3.00%
20	8	0.006	0.010	-0.004	-66.67%	4.00%
20	9	0.006	0.010	-0.004	-66.67%	4.00%
20	10	0.007	0.010	-0.003	-42.86%	3.00%
20	11	0.006	0.010	-0.004	-66.67%	4.00%
20	12	0.006	0.010	-0.004	-66.67%	4.00%
20	13	0.006	0.010	-0.004	-66.67%	4.00%
20	14	0.006	0.010	-0.004	-66.67%	4.00%
20	15	0.008	0.009	-0.001	-12.50%	1.00%
20	16	0.007	0.009	-0.002	-28.57%	2.00%
20	17	0.008	0.009	-0.001	-12.50%	1.00%
20	18	0.008	0.009	-0.001	-12.50%	1.00%
20	19	0.008	0.009	-0.001	-12.50%	1.00%
20	20	0.008	0.009	-0.001	-12.50%	1.00%
20	21	0.008	0.009	-0.001	-12.50%	1.00%
20	22	0.008	0.009	-0.001	-12.50%	1.00%
20	23	0.008	0.009	-0.001	-12.50%	1.00%
20	24	0.008	0.008	0.000	0.00%	0.00%
20	25	0.008	0.009	-0.001	-12.50%	1.00%
20	26	0.008	0.009	-0.001	-12.50%	1.00%
20	27	0.008	0.009	-0.001	-12.50%	1.00%
20	28	0.008	0.009	-0.001	-12.50%	1.00%
20	29	0.008	0.009	-0.001	-12.50%	1.00%
20	30	0.008	0.009	-0.001	-12.50%	1.00%
20	31	0.008	0.009	-0.001	-12.50%	1.00%
20	32	0.008	0.009	-0.001	-12.50%	1.00%
20	33	0.008	0.009	-0.001	-12.50%	1.00%
20	34	0.008	0.009	-0.001	-12.50%	1.00%
20	35	0.008	0.009	-0.001	-12.50%	1.00%
20	36	0.008	0.009	-0.001	-12.50%	1.00%
20	37	0.008	0.009	-0.001	-12.50%	1.00%
	Max	0.008	0.010	0.000	0.00%	4.00%
	Average	0.007	0.009	-0.002	-31.16%	2.05%
	Min	0.006	0.008	-0.004	-66.67%	0.00%
	Std Dev	0.001	0.001	0.001	25.04%	1.41%



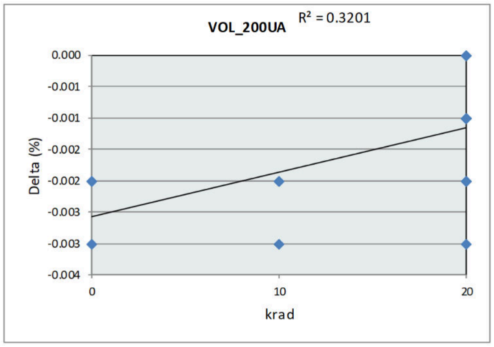
	VOL_50UA		
Test Site			
Tester			
Test Number			
Max Limit	0.1	V	
Min Limit	0	V	
krad	0	10	20
LL	0.000	0.000	0.000
Min	0.010	0.010	0.008
Average	0.010	0.010	0.009
Max	0.010	0.010	0.010
UL	0.100	0.100	0.100



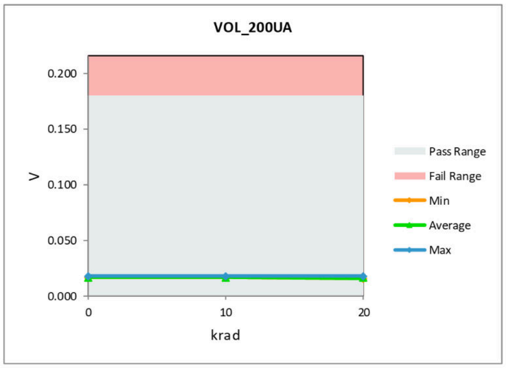
TID Report
SN54SLC8T245-SEP

	VOL_200UA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.18	0.18
Min Limit	0	0

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.015	0.017	-0.002	-13.33%	1.11%
0	2	0.015	0.017	-0.002	-13.33%	1.11%
0	3	0.015	0.018	-0.003	-20.00%	1.67%
10	4	0.015	0.017	-0.002	-13.33%	1.11%
10	5	0.015	0.018	-0.003	-20.00%	1.67%
10	6	0.015	0.017	-0.002	-13.33%	1.11%
20	7	0.015	0.017	-0.002	-13.33%	1.11%
20	8	0.015	0.017	-0.002	-13.33%	1.11%
20	9	0.016	0.017	-0.001	-6.25%	0.56%
20	10	0.015	0.017	-0.002	-13.33%	1.11%
20	11	0.015	0.018	-0.003	-20.00%	1.67%
20	12	0.016	0.017	-0.001	-6.25%	0.56%
20	13	0.015	0.017	-0.002	-13.33%	1.11%
20	14	0.016	0.017	-0.001	-6.25%	0.56%
20	15	0.015	0.016	-0.001	-6.67%	0.56%
20	16	0.015	0.016	-0.001	-6.67%	0.56%
20	17	0.016	0.017	-0.001	-6.25%	0.56%
20	18	0.016	0.017	-0.001	-6.25%	0.56%
20	19	0.016	0.017	-0.001	-6.25%	0.56%
20	20	0.016	0.016	0.000	0.00%	0.00%
20	21	0.016	0.017	-0.001	-6.25%	0.56%
20	22	0.016	0.017	-0.001	-6.25%	0.56%
20	23	0.016	0.017	-0.001	-6.25%	0.56%
20	24	0.016	0.016	0.000	0.00%	0.00%
20	25	0.016	0.017	-0.001	-6.25%	0.56%
20	26	0.016	0.017	-0.001	-6.25%	0.56%
20	27	0.016	0.017	-0.001	-6.25%	0.56%
20	28	0.016	0.017	-0.001	-6.25%	0.56%
20	29	0.016	0.017	-0.001	-6.25%	0.56%
20	30	0.016	0.017	-0.001	-6.25%	0.56%
20	31	0.016	0.016	0.000	0.00%	0.00%
20	32	0.016	0.017	-0.001	-6.25%	0.56%
20	33	0.016	0.017	-0.001	-6.25%	0.56%
20	34	0.016	0.017	-0.001	-6.25%	0.56%
20	35	0.015	0.017	-0.002	-13.33%	1.11%
20	36	0.016	0.017	-0.001	-6.25%	0.56%
20	37	0.016	0.017	-0.001	-6.25%	0.56%
	Max	0.016	0.018	0.000	0.00%	1.67%
	Average	0.016	0.017	-0.001	-8.60%	0.74%
	Min	0.015	0.016	-0.003	-20.00%	0.00%
	Std Dev	0.000	0.000	0.001	5.09%	0.42%



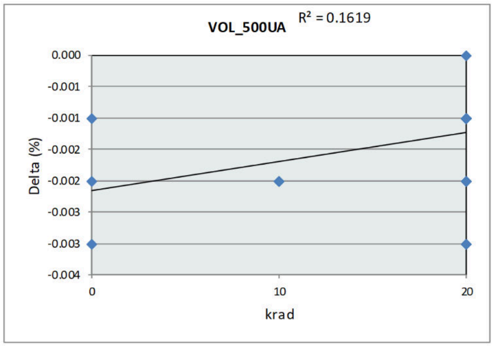
	VOL_200UA		
Test Site			
Tester			
Test Number			
Max Limit	0.18	V	
Min Limit	0	V	
krad	0	10	20
LL	0.000	0.000	0.000
Min	0.017	0.017	0.016
Average	0.017	0.017	0.017
Max	0.018	0.018	0.018
UL	0.180	0.180	0.180



TID Report
SN54SLC8T245-SEP

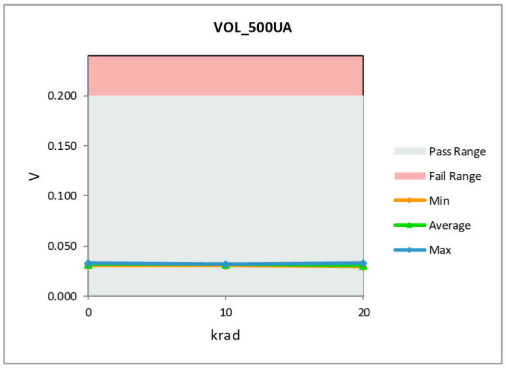
	VOL_500UA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.2	0.2
Min Limit	0	0

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.030	0.031	-0.001	-3.33%	0.50%
0	2	0.030	0.032	-0.002	-6.67%	1.00%
0	3	0.030	0.033	-0.003	-10.00%	1.50%
10	4	0.029	0.031	-0.002	-6.90%	1.00%
10	5	0.030	0.032	-0.002	-6.67%	1.00%
10	6	0.029	0.031	-0.002	-6.90%	1.00%
20	7	0.029	0.031	-0.002	-6.90%	1.00%
20	8	0.030	0.031	-0.001	-3.33%	0.50%
20	9	0.030	0.031	-0.001	-3.33%	0.50%
20	10	0.029	0.032	-0.003	-10.34%	1.50%
20	11	0.030	0.032	-0.002	-6.67%	1.00%
20	12	0.030	0.032	-0.002	-6.67%	1.00%
20	13	0.030	0.031	-0.001	-3.33%	0.50%
20	14	0.030	0.032	-0.002	-6.67%	1.00%
20	15	0.029	0.030	-0.001	-3.45%	0.50%
20	16	0.029	0.030	-0.001	-3.45%	0.50%
20	17	0.030	0.031	-0.001	-3.33%	0.50%
20	18	0.030	0.031	-0.001	-3.33%	0.50%
20	19	0.030	0.031	-0.001	-3.33%	0.50%
20	20	0.030	0.031	-0.001	-3.33%	0.50%
20	21	0.030	0.031	-0.001	-3.33%	0.50%
20	22	0.030	0.031	-0.001	-3.33%	0.50%
20	23	0.030	0.031	-0.001	-3.33%	0.50%
20	24	0.030	0.031	-0.001	-3.33%	0.50%
20	25	0.030	0.031	-0.001	-3.33%	0.50%
20	26	0.030	0.031	-0.001	-3.33%	0.50%
20	27	0.030	0.033	-0.003	-10.00%	1.50%
20	28	0.030	0.031	-0.001	-3.33%	0.50%
20	29	0.030	0.031	-0.001	-3.33%	0.50%
20	30	0.030	0.031	-0.001	-3.33%	0.50%
20	31	0.030	0.031	-0.001	-3.33%	0.50%
20	32	0.030	0.031	-0.001	-3.33%	0.50%
20	33	0.030	0.030	0.000	0.00%	0.00%
20	34	0.030	0.031	-0.001	-3.33%	0.50%
20	35	0.030	0.031	-0.001	-3.33%	0.50%
20	36	0.030	0.031	-0.001	-3.33%	0.50%
20	37	0.030	0.031	-0.001	-3.33%	0.50%
	Max	0.030	0.033	0.000	0.00%	1.50%
	Average	0.030	0.031	-0.001	-4.54%	0.68%
	Min	0.029	0.030	-0.003	-10.34%	0.00%
	Std Dev	0.000	0.001	0.001	2.29%	0.34%



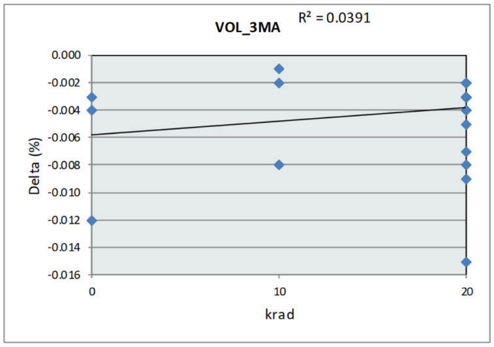
	VOL_500UA		
Test Site			
Tester			
Test Number			
Max Limit	0.2	V	
Min Limit	0	V	

krad	0	10	20
LL	0.000	0.000	0.000
Min	0.031	0.031	0.030
Average	0.032	0.031	0.031
Max	0.033	0.032	0.033
UL	0.200	0.200	0.200

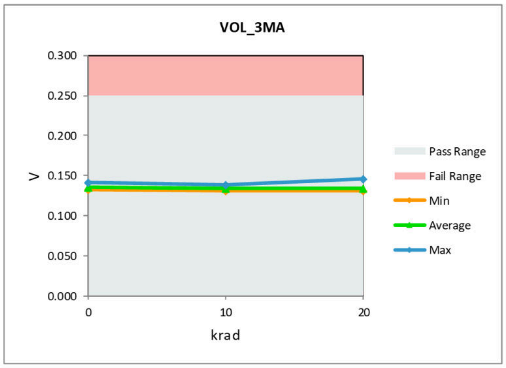


TID Report
SN54SLC8T245-SEP

		VOL_3MA				
	Test Site					
	Tester					
	Test Number					
	Unit	V	V			
	Max Limit	0.25	0.25			
	Min Limit	0	0			
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.129	0.133	-0.004	-3.10%	1.60%
0	2	0.130	0.133	-0.003	-2.31%	1.20%
0	3	0.130	0.142	-0.012	-9.23%	4.80%
10	4	0.130	0.132	-0.002	-1.54%	0.80%
10	5	0.130	0.138	-0.008	-6.15%	3.20%
10	6	0.130	0.131	-0.001	-0.77%	0.40%
20	7	0.129	0.133	-0.004	-3.10%	1.60%
20	8	0.130	0.132	-0.002	-1.54%	0.80%
20	9	0.130	0.134	-0.004	-3.08%	1.60%
20	10	0.129	0.134	-0.005	-3.88%	2.00%
20	11	0.130	0.133	-0.003	-2.31%	1.20%
20	12	0.130	0.139	-0.009	-6.92%	3.60%
20	13	0.130	0.133	-0.003	-2.31%	1.20%
20	14	0.130	0.138	-0.008	-6.15%	3.20%
20	15	0.130	0.132	-0.002	-1.54%	0.80%
20	16	0.129	0.132	-0.003	-2.33%	1.20%
20	17	0.131	0.134	-0.003	-2.29%	1.20%
20	18	0.131	0.134	-0.003	-2.29%	1.20%
20	19	0.131	0.134	-0.003	-2.29%	1.20%
20	20	0.131	0.134	-0.003	-2.29%	1.20%
20	21	0.131	0.134	-0.003	-2.29%	1.20%
20	22	0.131	0.134	-0.003	-2.29%	1.20%
20	23	0.132	0.134	-0.002	-1.52%	0.80%
20	24	0.131	0.134	-0.003	-2.29%	1.20%
20	25	0.131	0.134	-0.003	-2.29%	1.20%
20	26	0.131	0.134	-0.003	-2.29%	1.20%
20	27	0.131	0.146	-0.015	-11.45%	6.00%
20	28	0.131	0.138	-0.007	-5.34%	2.80%
20	29	0.131	0.134	-0.003	-2.29%	1.20%
20	30	0.131	0.134	-0.003	-2.29%	1.20%
20	31	0.131	0.134	-0.003	-2.29%	1.20%
20	32	0.131	0.135	-0.004	-3.05%	1.60%
20	33	0.131	0.133	-0.002	-1.53%	0.80%
20	34	0.132	0.135	-0.003	-2.27%	1.20%
20	35	0.131	0.134	-0.003	-2.29%	1.20%
20	36	0.131	0.134	-0.003	-2.29%	1.20%
20	37	0.131	0.134	-0.003	-2.29%	1.20%
	Max	0.132	0.146	-0.001	-0.77%	6.00%
	Average	0.131	0.135	-0.004	-3.13%	1.63%
	Min	0.129	0.131	-0.015	-11.45%	0.40%
	Std Dev	0.001	0.003	0.003	2.22%	1.16%



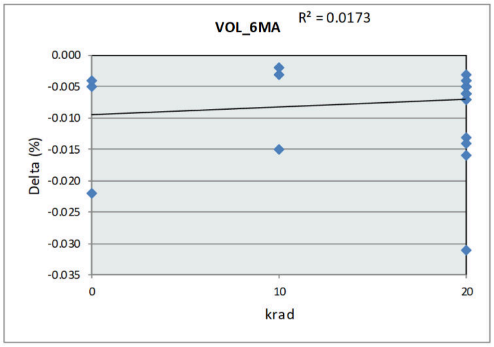
	VOL_3MA		
Test Site			
Tester			
Test Number			
Max Limit	0.25	V	
Min Limit	0	V	
krad	0	10	20
LL	0.000	0.000	0.000
Min	0.133	0.131	0.132
Average	0.136	0.134	0.135
Max	0.142	0.138	0.146
UL	0.250	0.250	0.250



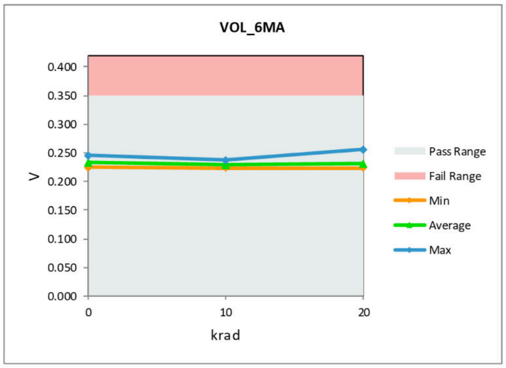
TID Report
SN54SLC8T245-SEP

	VOL_6MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.35	0.35
Min Limit	0	0

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.221	0.226	-0.005	-2.26%	1.43%
0	2	0.223	0.227	-0.004	-1.79%	1.14%
0	3	0.223	0.245	-0.022	-9.87%	6.29%
10	4	0.223	0.226	-0.003	-1.35%	0.86%
10	5	0.222	0.237	-0.015	-6.76%	4.29%
10	6	0.223	0.225	-0.002	-0.90%	0.57%
20	7	0.222	0.227	-0.005	-2.25%	1.43%
20	8	0.222	0.225	-0.003	-1.35%	0.86%
20	9	0.223	0.229	-0.006	-2.69%	1.71%
20	10	0.222	0.229	-0.007	-3.15%	2.00%
20	11	0.222	0.227	-0.005	-2.25%	1.43%
20	12	0.223	0.239	-0.016	-7.17%	4.57%
20	13	0.222	0.228	-0.006	-2.70%	1.71%
20	14	0.223	0.236	-0.013	-5.83%	3.71%
20	15	0.224	0.230	-0.006	-2.68%	1.71%
20	16	0.224	0.229	-0.005	-2.23%	1.43%
20	17	0.226	0.231	-0.005	-2.21%	1.43%
20	18	0.226	0.232	-0.006	-2.65%	1.71%
20	19	0.226	0.232	-0.006	-2.65%	1.71%
20	20	0.226	0.231	-0.005	-2.21%	1.43%
20	21	0.226	0.232	-0.006	-2.65%	1.71%
20	22	0.226	0.232	-0.006	-2.65%	1.71%
20	23	0.227	0.232	-0.005	-2.20%	1.43%
20	24	0.226	0.231	-0.005	-2.21%	1.43%
20	25	0.226	0.232	-0.006	-2.65%	1.71%
20	26	0.226	0.231	-0.005	-2.21%	1.43%
20	27	0.226	0.257	-0.031	-13.72%	8.86%
20	28	0.226	0.240	-0.014	-6.19%	4.00%
20	29	0.226	0.230	-0.004	-1.77%	1.14%
20	30	0.226	0.231	-0.005	-2.21%	1.43%
20	31	0.226	0.231	-0.005	-2.21%	1.43%
20	32	0.226	0.232	-0.006	-2.65%	1.71%
20	33	0.226	0.231	-0.005	-2.21%	1.43%
20	34	0.227	0.234	-0.007	-3.08%	2.00%
20	35	0.226	0.232	-0.006	-2.65%	1.71%
20	36	0.226	0.232	-0.006	-2.65%	1.71%
20	37	0.226	0.230	-0.004	-1.77%	1.14%
	Max	0.227	0.257	-0.002	-0.90%	8.86%
	Average	0.225	0.232	-0.007	-3.26%	2.09%
	Min	0.221	0.225	-0.031	-13.72%	0.57%
	Std Dev	0.002	0.006	0.006	2.54%	1.63%



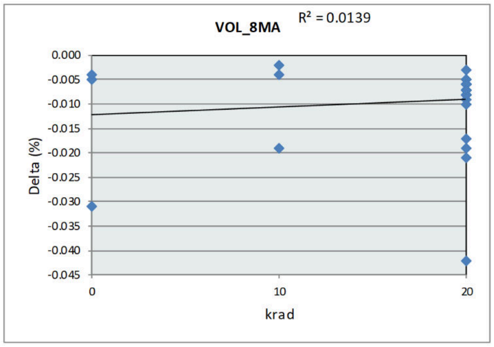
	VOL_6MA		
Test Site			
Tester			
Test Number			
Max Limit	0.35	V	
Min Limit	0	V	
krad	0	10	20
LL	0.000	0.000	0.000
Min	0.226	0.225	0.225
Average	0.233	0.229	0.232
Max	0.245	0.237	0.257
UL	0.350	0.350	0.350



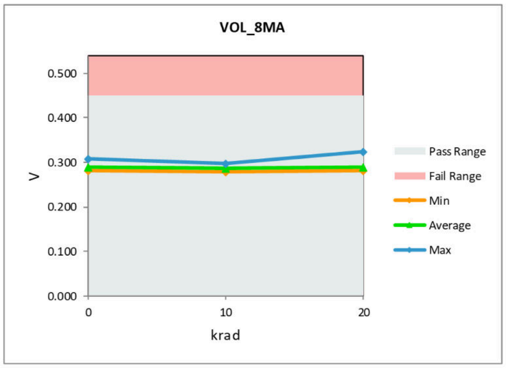
TID Report
SN54SLC8T245-SEP

	VOL_8MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.45	0.45
Min Limit	0	0

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.276	0.281	-0.005	-1.81%	1.11%
0	2	0.279	0.283	-0.004	-1.43%	0.89%
0	3	0.277	0.308	-0.031	-11.19%	6.89%
10	4	0.278	0.282	-0.004	-1.44%	0.89%
10	5	0.278	0.297	-0.019	-6.83%	4.22%
10	6	0.278	0.280	-0.002	-0.72%	0.44%
20	7	0.277	0.284	-0.007	-2.53%	1.56%
20	8	0.278	0.281	-0.003	-1.08%	0.67%
20	9	0.278	0.286	-0.008	-2.88%	1.78%
20	10	0.277	0.286	-0.009	-3.25%	2.00%
20	11	0.278	0.284	-0.006	-2.16%	1.33%
20	12	0.278	0.299	-0.021	-7.55%	4.67%
20	13	0.278	0.284	-0.006	-2.16%	1.33%
20	14	0.278	0.295	-0.017	-6.12%	3.78%
20	15	0.282	0.287	-0.005	-1.77%	1.11%
20	16	0.281	0.287	-0.006	-2.14%	1.33%
20	17	0.283	0.290	-0.007	-2.47%	1.56%
20	18	0.283	0.291	-0.008	-2.83%	1.78%
20	19	0.283	0.290	-0.007	-2.47%	1.56%
20	20	0.283	0.290	-0.007	-2.47%	1.56%
20	21	0.284	0.291	-0.007	-2.46%	1.56%
20	22	0.283	0.291	-0.008	-2.83%	1.78%
20	23	0.284	0.290	-0.006	-2.11%	1.33%
20	24	0.283	0.291	-0.008	-2.83%	1.78%
20	25	0.283	0.291	-0.008	-2.83%	1.78%
20	26	0.284	0.290	-0.006	-2.11%	1.33%
20	27	0.283	0.325	-0.042	-14.84%	9.33%
20	28	0.283	0.302	-0.019	-6.71%	4.22%
20	29	0.284	0.289	-0.005	-1.76%	1.11%
20	30	0.282	0.289	-0.007	-2.48%	1.56%
20	31	0.283	0.289	-0.006	-2.12%	1.33%
20	32	0.283	0.291	-0.008	-2.83%	1.78%
20	33	0.284	0.290	-0.006	-2.11%	1.33%
20	34	0.283	0.293	-0.010	-3.53%	2.22%
20	35	0.283	0.291	-0.008	-2.83%	1.78%
20	36	0.284	0.290	-0.006	-2.11%	1.33%
20	37	0.283	0.290	-0.007	-2.47%	1.56%
	Max	0.284	0.325	-0.002	-0.72%	9.33%
	Average	0.281	0.290	-0.009	-3.36%	2.10%
	Min	0.276	0.280	-0.042	-14.84%	0.44%
	Std Dev	0.003	0.008	0.008	2.83%	1.76%



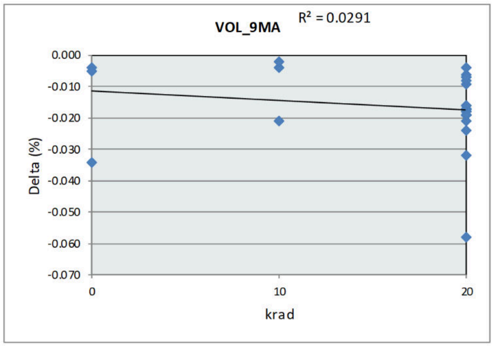
	VOL_8MA		
Test Site			
Tester			
Test Number			
Max Limit	0.45	V	
Min Limit	0	V	
krad	0	10	20
LL	0.000	0.000	0.000
Min	0.281	0.280	0.281
Average	0.291	0.286	0.291
Max	0.308	0.297	0.325
UL	0.450	0.450	0.450



TID Report
SN54SLC8T245-SEP

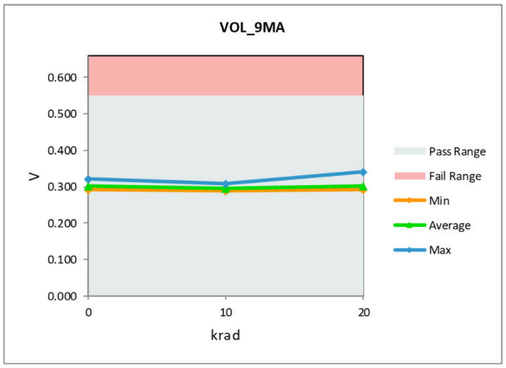
	VOL_9MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.55	0.55
Min Limit	0	0

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.287	0.291	-0.004	-1.39%	0.73%
0	2	0.288	0.293	-0.005	-1.74%	0.91%
0	3	0.287	0.321	-0.034	-11.85%	6.18%
10	4	0.288	0.292	-0.004	-1.39%	0.73%
10	5	0.288	0.309	-0.021	-7.29%	3.82%
10	6	0.288	0.290	-0.002	-0.69%	0.36%
20	7	0.288	0.294	-0.006	-2.08%	1.09%
20	8	0.288	0.292	-0.004	-1.39%	0.73%
20	9	0.288	0.297	-0.009	-3.13%	1.64%
20	10	0.288	0.296	-0.008	-2.78%	1.45%
20	11	0.288	0.295	-0.007	-2.43%	1.27%
20	12	0.288	0.312	-0.024	-8.33%	4.36%
20	13	0.288	0.295	-0.007	-2.43%	1.27%
20	14	0.288	0.307	-0.019	-6.60%	3.45%
20	15	0.283	0.300	-0.017	-6.01%	3.09%
20	16	0.283	0.299	-0.016	-5.65%	2.91%
20	17	0.284	0.302	-0.018	-6.34%	3.27%
20	18	0.285	0.302	-0.017	-5.96%	3.09%
20	19	0.284	0.303	-0.019	-6.69%	3.45%
20	20	0.285	0.302	-0.017	-5.96%	3.09%
20	21	0.285	0.302	-0.017	-5.96%	3.09%
20	22	0.283	0.302	-0.019	-6.71%	3.45%
20	23	0.285	0.302	-0.017	-5.96%	3.09%
20	24	0.284	0.303	-0.019	-6.69%	3.45%
20	25	0.285	0.303	-0.018	-6.32%	3.27%
20	26	0.285	0.302	-0.017	-5.96%	3.09%
20	27	0.284	0.342	-0.058	-20.42%	10.55%
20	28	0.285	0.317	-0.032	-11.23%	5.82%
20	29	0.284	0.301	-0.017	-5.99%	3.09%
20	30	0.284	0.301	-0.017	-5.99%	3.09%
20	31	0.283	0.302	-0.019	-6.71%	3.45%
20	32	0.284	0.302	-0.018	-6.34%	3.27%
20	33	0.285	0.302	-0.017	-5.96%	3.09%
20	34	0.284	0.305	-0.021	-7.39%	3.82%
20	35	0.285	0.302	-0.017	-5.96%	3.09%
20	36	0.284	0.303	-0.019	-6.69%	3.45%
20	37	0.285	0.301	-0.016	-5.61%	2.91%
	Max	0.288	0.342	-0.002	-0.69%	10.55%
	Average	0.286	0.302	-0.017	-5.84%	3.03%
	Min	0.283	0.290	-0.058	-20.42%	0.36%
	Std Dev	0.002	0.009	0.010	3.54%	1.83%



	VOL_9MA	
Test Site		
Tester		
Test Number		
Max Limit	0.55	V
Min Limit	0	V

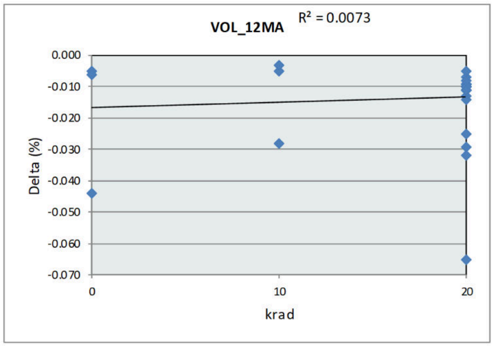
krad	0	10	20
LL	0.000	0.000	0.000
Min	0.291	0.290	0.292
Average	0.302	0.297	0.303
Max	0.321	0.309	0.342
UL	0.550	0.550	0.550



TID Report
SN54SLC8T245-SEP

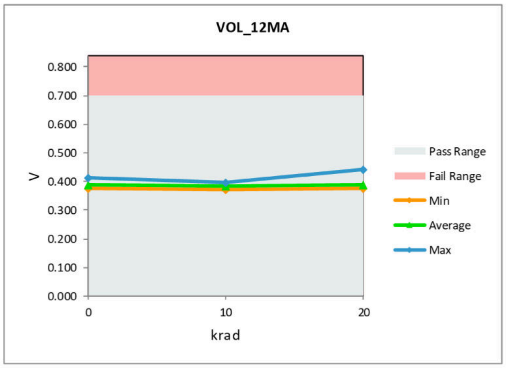
	VOL_12MA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.7	0.7
Min Limit	0	0

krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.369	0.374	-0.005	-1.36%	0.71%
0	2	0.371	0.377	-0.006	-1.62%	0.86%
0	3	0.370	0.414	-0.044	-11.89%	6.29%
10	4	0.371	0.376	-0.005	-1.35%	0.71%
10	5	0.370	0.398	-0.028	-7.57%	4.00%
10	6	0.370	0.373	-0.003	-0.81%	0.43%
20	7	0.371	0.378	-0.007	-1.89%	1.00%
20	8	0.370	0.375	-0.005	-1.35%	0.71%
20	9	0.370	0.383	-0.013	-3.51%	1.86%
20	10	0.371	0.381	-0.010	-2.70%	1.43%
20	11	0.370	0.380	-0.010	-2.70%	1.43%
20	12	0.370	0.402	-0.032	-8.65%	4.57%
20	13	0.370	0.379	-0.009	-2.43%	1.29%
20	14	0.370	0.395	-0.025	-6.76%	3.57%
20	15	0.377	0.386	-0.009	-2.39%	1.29%
20	16	0.377	0.387	-0.010	-2.65%	1.43%
20	17	0.379	0.388	-0.009	-2.37%	1.29%
20	18	0.380	0.390	-0.010	-2.63%	1.43%
20	19	0.379	0.389	-0.010	-2.64%	1.43%
20	20	0.380	0.389	-0.009	-2.37%	1.29%
20	21	0.380	0.390	-0.010	-2.63%	1.43%
20	22	0.378	0.389	-0.011	-2.91%	1.57%
20	23	0.379	0.388	-0.009	-2.37%	1.29%
20	24	0.379	0.389	-0.010	-2.64%	1.43%
20	25	0.379	0.390	-0.011	-2.90%	1.57%
20	26	0.379	0.389	-0.010	-2.64%	1.43%
20	27	0.378	0.443	-0.065	-17.20%	9.29%
20	28	0.379	0.408	-0.029	-7.65%	4.14%
20	29	0.379	0.388	-0.009	-2.37%	1.29%
20	30	0.377	0.388	-0.011	-2.92%	1.57%
20	31	0.378	0.388	-0.010	-2.65%	1.43%
20	32	0.378	0.389	-0.011	-2.91%	1.57%
20	33	0.379	0.389	-0.010	-2.64%	1.43%
20	34	0.379	0.393	-0.014	-3.69%	2.00%
20	35	0.379	0.390	-0.011	-2.90%	1.57%
20	36	0.378	0.389	-0.011	-2.91%	1.57%
20	37	0.380	0.388	-0.008	-2.11%	1.14%
	Max	0.380	0.443	-0.003	-0.81%	9.29%
	Average	0.375	0.389	-0.014	-3.67%	1.97%
	Min	0.369	0.373	-0.065	-17.20%	0.43%
	Std Dev	0.004	0.012	0.012	3.22%	1.72%



	VOL_12MA	
Test Site		
Tester		
Test Number		
Max Limit	0.7	V
Min Limit	0	V

krad	0	10	20
LL	0.000	0.000	0.000
Min	0.374	0.373	0.375
Average	0.388	0.382	0.390
Max	0.414	0.398	0.443
UL	0.700	0.700	0.700



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